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PRODUCT CATALOGUE

From nanometer to hectometer

we provide professional precision measurement solutions







Since established in 2002, Chotest Technology Inc. is focusing on the designing and manufacturing of precision dimensional measurement and calibration instruments.

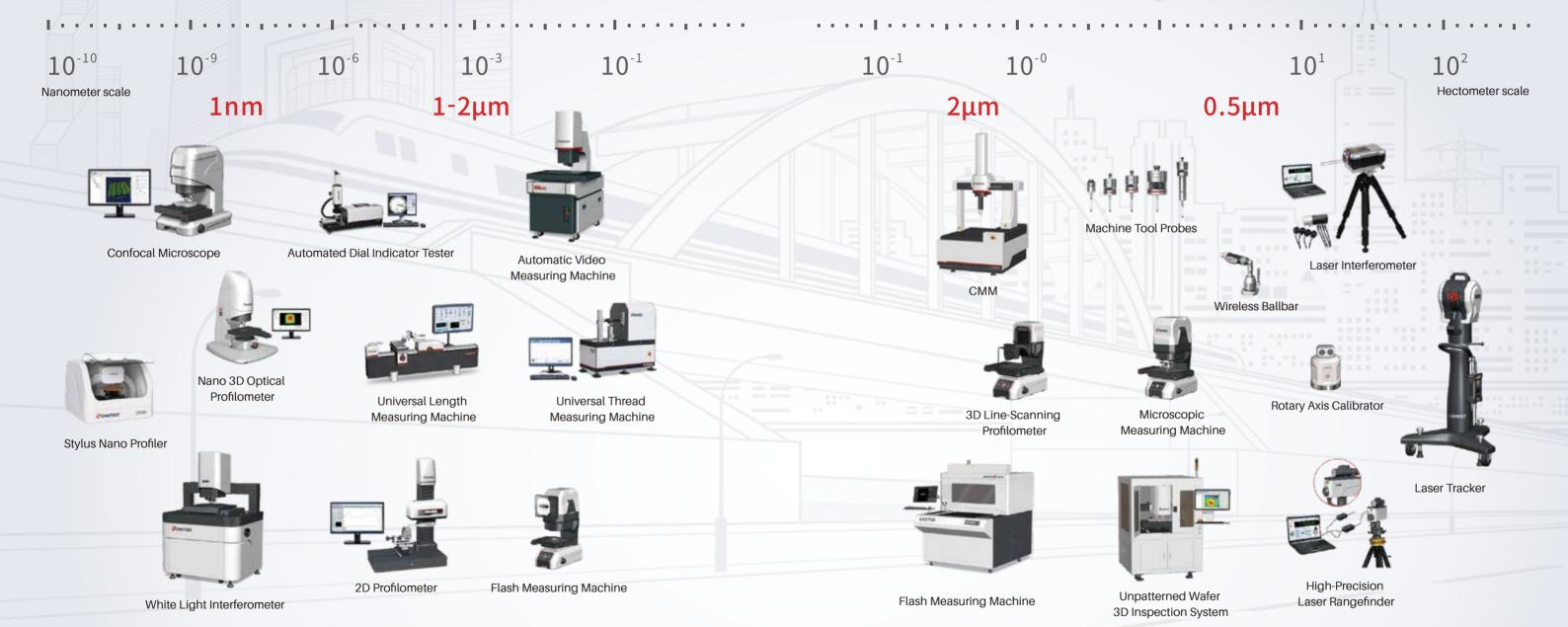
With more than decade professional technology accumulation,
Chotest has accumulated rich practical experience and set up a strong
team who is specialized in optics, machinery, electronics and
information technology. At present, CHOTEST has more than 100
technology patents and software intellectual property rights. With
competence in Micro-Nano motion, 3D Reconstruction of Micro-Nano

measurement, 3D Form and Surface Analysis of Micro-Nano measurement, Large-scale 3D Measurement, Precision Sensing Probe and Image processing technology, Chotest is capable to provide the customers with professional precision measurement solution in domains from Nanometer to Hectometer.

Our products are widely used by public metrology labs and quality inspection workshops in the automotive, aerospace, machinery, metallurgy, power, and petrochemical industries. Chotest's service network is covered more than 30 provinces in China, and is also focusing on the development in overseas markets like Europe and APAC. The goal of Chotest is to provide high-end dimensional measurement equipment to manufacturing industry all over the world.

From nanometer to hectometer

we provide professional precision measurement solutions



Measurement Solutions for Full-Scale Chain

We are committed to providing full-scale chain solutions for different customers and different industries. With our expertise, technologies, various instruments and software, we can reduce costs and increase efficiency for our customers, at the same time, continuously improve product quality, which helps customers to enhance their market competitiveness.







Aviation/Aerospace/Shipbuilding Industry Application

As an important part of the equipment manufacturing industry, the aerospace and Shipbuilding industry is an important field for implementing the innovation-driven development strategy and an important support for building a manufacturing power. Chotest provides a full range of dimension measurement solutions in the industrial chain system including the whole machine manufacturing, power system, key components, key basic materials, etc



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P91



For parts such as aero-engines and gear blades, Chotest Coordinate Measuring Machines Mars series can provide high-efficient and precise dimensional inspection

CMM,coming



With the high measurement accuracy and large measurement range, Chotest GTS laser tracker is used in various assembly application scenarios such as airplane & rocket & vessel assembly and profile measurement.

P73





Chotest Video Measuring Machines/
Flash Measuring Machines support
non-contact fast and magnified
measurement. The software Vision X
has more than 90 measurement
functions, and has special
measurement tools for sealing rings,
springs, gears, threads and other
workpieces. It can perform simple,
fast and accurate measurement,
and it is the best measurement
method for small parts or small-size
features, thin-walled parts, and soft
parts.

P21/P34



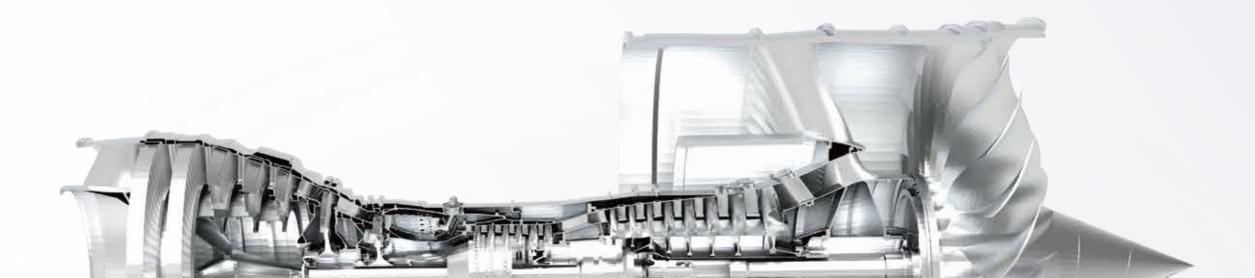
Chotest high-precision Profilometer SJ5730, with 2 in 1(roughness and profile) measurement module, is often used to measure the surface profile shape and roughness of the engine fuel nozzles and engine crankshaft connecting rods.

P97



Chotest universal length measuring machine SJ5100 is often used to calibrate measuring gauges in aerospace metrology labs and to measure the ultra-high-precision piston rods, which is one of the core components of aero- engines.

P123



Automotive/New Energy Industry Application

The automotive and new energy industries are witnessing rapid growth, driven by the rapid expansion of new energy vehicles. Chotest provides solutions for various dimension measurements in the entire production process, from battery production stages, modules, battery packs, electric motor components, electronic control modules, to complete vehicle bodies.

Automotive Research Institute



Chotest Universal Thread Measuring Machines can calibrate the full parameters of the thread, helping the precision manufacturing of automobiles.

P127



Bodywork

Chotest Coordinate measuring machines Mars series support high precision and high speed measurement for car body.

CMM,coming



Chotest universal length measuring machine SJ5100 is used to calibrate the gauges and other measuring tools, which are widely used in major automobile research institutes.

P123



Chotest Laser tracker is a flexible and large-range measurement method for the car body, and has been recognized and accepted by the automobile OEM and their supporting factories. As a supplement to the Chotest Coordinate Measuring machine, Chotest Laser Tracker is appearing more and more in the workshops of automobile OEM.

P74



Chotest fully automatic dial indicator testing machines SJ2000 Series can automatically calibrate various plunger dial indicators, digital dial indicators, dial test gauges, dail bore gauges, mechanical comparators, etc.

P131



Chotest Coordinate measuring machine Mars series is used in the design and trial production of new models.

CMM,coming



Chotest Video Measuring Machines can measure the sizes of various auto

P21



Chotest 2D profilometers SJ5700 series can inspect the tiny dimensions of auto parts, and ensure the high processing accuracy of parts.

P91





Chotest Coordinate Measuring machine is crucial to ensuring the quality and performance of the powertrain and even the entire vehicle.

CMM,coming



Chotest 2D profilometers SJ5700 series can measure the tiny dimensions of automobile engines, gearboxes and other parts.

D01



Chotest Video Measuring
Machines / Flash Measuring
Machines can quickly and
accurately measure the XY sizes of
small auto parts.

P21/P34

Automotive parts



Chotest Coordinate Measuring machine is an ideal solution for geometric measurement and quality control of cylinder parts.

CMM,coming



Chotest horizontal Flash Measuring Machine VX5000 series can easily measure the size of shaft parts, making the measurement process simple, efficient and accurate.

P53



Chotest Machine tool probes PO series can control the machining process of auto parts, and realize large-scale on-line measurement of parts after machining, ensure machining accuracy.

P109



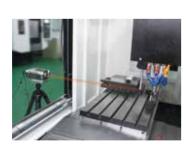
Chotest 2D profilometers SJ5700 series can measure the tiny dimensions of automobile cylinder head parts.

P91



Chotest Nano 3D Optical Surface Profilometers can measure the surface profile of the fuel injector at the sub-nanometer level.

P57



Chotest Laser interferometer SJ6000 can calibrate and compensate CNC machine tools for the position accuracy (positioning accuracy repeatability, positioning accuracy, etc.) and geometric accuracy (pitch and yaw angle, straightness, verticality, etc.).

P79



Chotest Video Measuring
Machines/ Flash Measuring
Machines can efficiently measure
the diameter and center distance of
the connecting rod.

P21/P34



Chotest 2D profilometers SJ5700 series can measure both roughness and profile of the workpieces.

P91

Camera/LIDAR



Chotest Laser interferometer SJ6000 can calibrate and compensate CNC machine tools for the position accuracy (positioning accuracy repeatability, positioning accuracy, etc.) and geometric accuracy (pitch and yaw angle, straightness, squareness, etc.).



Chotest Nano 3D Optical Surface Profilometers can measure the surface flatness &roughness and 3D shape of the radar chip.

P57

Power Battery

P79



Chotest Coordinate Measuring machine achieves precision measurement of length & width, flatness, assembly hole position and step height of battery pack.

CMM,coming `



Chotest Flash Measuring
Machines/ Video Measuring
Machines provide a precision and
stable measurement solution for
top covers of power battery.

P21/P34





3C Electronics Industry Application

Chotest provides a series of measurement equipment to control the product processing quality in the 3C industry. The software presents datafication results, which can be used to improve design and re-producing.

The adjoint geometric measurement system solves the geometric measurement problems in the whole production process, and realizes the systematic and efficient process control and quality management



Chotest Flash Measuring Machines/ Video Measuring Machines can realise high-precision measurements of different sizes and varying structures by one click.

P21/P34



Chotest Machine tool probes PO series are 100% tested by self -developed inspection equipment to ensure quality and stability; Completely replaceable with international famous probes. Laser interferometer SJ6000 and Rotary axis calibrator WR50 are used to calibrate the guide rail of CNC machine tools. Moreover, Chotest Wireless ballbar MT21 can diagnose CNC machine tools' performance quickly.

P113



Measurement head + automation module + customized 2D and 3D automatic dimensional measurement functions constitute a efficient measurement solution for some special & difficult scenarios.





Chotest Nano 3D Optical Surface Profilometers can measure the roughness, flatness and step height of sapphire screens, phone glass screens, ink screens, etc.

P57



Chotest 2D profilometers SJ5730 series, with micro measuring force and high precision performance, is suitable for fast measurement of easy-to-scratch surfaces, such as the thickness of screen-printing ink on the front cover of mobile phones.

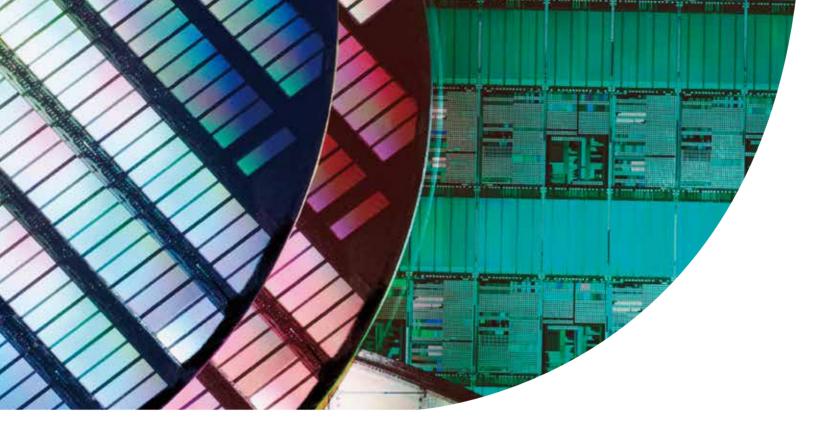
P97

In the 3C field, Chotest coordinate measuring machine is not only used in inspection of the plane sizes and GD &T, but also used in measurement of the curved surfaces, mobile phone screen corners,

CMM,coming

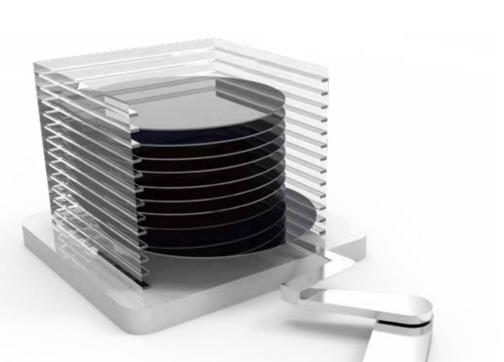
chamfers. etc.

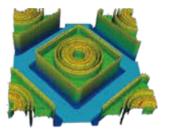
P109





In recent years, with higher and higher requirements to product quality in the chip manufacturing industry, more sophisticated measurement instruments are required to ensure product quality. Integrating self-developed software algorithms, Chotest precision measurement equipment perfectly caters for this kind of demands.





Chotest Nano 3D Optical Surface Profilometer is a non-contact scanning method to achieve 3D re-construction of the sample surface with ultra-high repeatability & accuracy, and obtains relative 2D and 3D measurement data.

P57



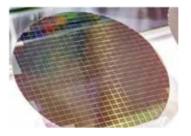
Unpatterned Wafer 3D Inspection System WD4000 adopts white light confocal probes and white light interferometry probe to scan and reconstruct 3D surface topagraphy of the wafer, then obtains the relative 2D and 3D parameters of thickness, BOW, WARP, flatness, line roughness, and Total Thickness Variation (TTV).

P113



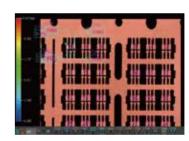
Patterned Wafer Critical Dimension & Overlay Measurement System can not only inspect the critical dimensions of wafer and the offset of overlay, but also measure the 3D surface form and roughness of wafer at the sub-nanometer level. Automatic robot arm can load and upload the test objects aumatically, which helps to achieve fully automated production in the workshop.

P117



Chotest Confocal microscope VT6000 series can reconstruct surface 3D topography by non-contact scanning, and has better imaging effects on surface with large slopes. It is be widely used in semiconductor manufacturing and packaging process inspection.

P67



Chotest Video Measuring Machines/-Flash Measuring Machines are mainly used in semiconductor packaging process, and they measure the substrates, lead frames, ceramic parts efficiently by one-click.

P21/P34



Chotest Stylus Nano Profiler CP200 can measure the film thickness & step height, surface topography and surface waviness & roughness by contact scanning. Thanks to micro measuring force, CP200 absolutely does not scratch the surface of test object at all.

P107



Optical Measurement Instrument	S		P19
Video Measuring Machines CHT Series	P21	Confocal Microscope VT6000 Series · · · · · · · · ·	P67
Video Measuring Machines Novator Series · · · · · · · · · · · · · · · · · · ·	P31	Microscopic Measuring Machine MX3200 · · ·	P71
Flash Measuring Machines VX Series ·····	P34	Laser Tracker GTS3000 Series · · · · · · · · · · · · · · · · · · ·	P77
Flash Measuring Machines Hybrid Series	P55	Laser Tracker GTS6000 Series · · · · · · · · · · · · · · · · · · ·	P78
3D Optical Surface Profilometer SuperView W1	P57	Laser interferometer SJ6000	P79
3D Optical Surface Profilometer SuperView W3	P61	Rotary Axis Calibrator WR50 · · · · · · · · · · · · · · · · · · ·	P83
3D Optical Surface Profilometer SuperView W5 ·	P63	Wireless Ballbar MT21 · · · · · · · · · · · · · · · · · · ·	P87
White Light Interferometry Probe SuperView WX100	P65		
Contact Measurement Instrumen	ts		P89
ntelligent Profilometer SJ5780 Series ·	- P91	Economic Profilometers SJ5718 Series	- P105

Intelligent Profilometer SJ5780 Series ·	P91	Economic Profilometers SJ5718 Series P105
Profilometers for Optics Surface SJ5720-OPT Series	P93	Stylus Nano Profiler CP200 P107
Profilometers SJ5730 Series · · · · · · · · · · · · · · · · · · ·	P97	Machine Tool Probes PO Series · P109
Profilometers SJ5760 Series ·····	P101	

	Professional Inspection Equipment		P111
Į	Inpatterned Wafer 3D Inspection System WD4000 P113	Patterned Wafer Critical Dimension & Overlay Measurement System BOKI_1000	P117

Dimensional Calibrators			PIZI
Universal Length Measuring Machines SJ5100 Series	P123	Automated Dial Indicator Testing Machines SJ2000 Series	P131
Universal Thread Measuring Machines SJ5200 Series	P129	002000 001100	
Universal Thread Measuring Machines SJ5500 Series	P130		



Optical Measuring Instrument

Automatic Video Measuring Machines CHT Series

Precision, Versatile

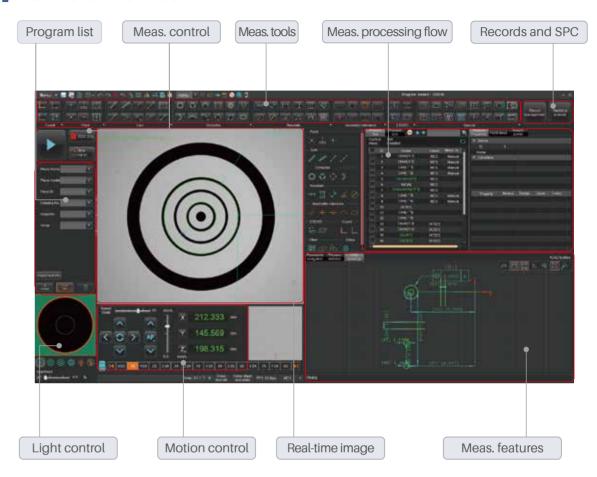


Description

Automatic video measuring machines CHT series covers different measurement ranges and offers powerful functionality. It can perform precise measurements of surface dimensions, contours, angles, positions, and geometric tolerances for various complex parts.

Automatic video measuring machines CHT series can be used in machinery, electronics, mold, injection molding, hardware, rubber, low-voltage electrical appliances, magnetic materials, precision stamping, connection Plug-ins, connectors, terminals, mobile phones, home appliances, printed circuit boards, medical equipment, clocks, knives, measurement and testing, etc.

Software Interface



User-Friendly Operation Interface

Auto data export

- Support exporting data to designated excel file according to designated template in real time
- Can output Excel, Word, PDF, TXT reports and AutoCAD files.
- Support Q-DAS transmission according to designated format.
- Support data exchanging via HTTP or socket protocol
- Output SPC analysis report, which includes statistical values (such as CA, PPK, CPK, PP, etc.) and control charts (such as mean and range charts, mean and standard deviation charts, median and range charts, single value and moving range chart).



Easy to operate

With user-friendly software, anyone can be trained to use it quickly







Save program



Place objects

Automatic Video Measuring Machines CHT Series

Place test objects on object table



Batch meas.

Measure all features by one-click

Measurement Function





Scanning to extract edge points, multi-segment edge point extraction, circular edge point extraction, ellipse extraction, frame selection to extract contour lines, focus points, closest points, etc.

Point, line, circle (center coordinates, radius, diameter), arc, center,

distance from hole to hole, distance from hole to edge, distance from arc center to hole, the distance from the center of the arc to the side,

the distance from the high point of the arc to the high point of the arc, and the distance from the intersection to the intersection, etc.

connecting two points, parallel line, perpendicular line, tangent line, bisector, Centerlines, line segment fusion, radius circle, three-line

Intersection point, center point, extreme point, end point, line

inscribed circle, two-line radius inscribed circle, etc.

Straightness, roundness, position, parallelism, symmetry, perpendicularity, concentricity, profile and position tolerance











Construction







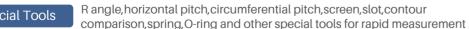








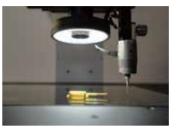
Instrument coordinate system, point to line, point to point, line to line and other workpiece coordinate systems; image registration coordinate system; Can translate, rotate, manually adjust the coordinate system



Support tolerance batch setting, scale classification, and color custom management

Flexible shooting and precise calculation

Support segmental programming control of surface light, transmitted light and coaxial light, automatically identify the measurement position, and obtain uniform and stable measurement results every time.



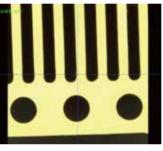
Ring light



Back light



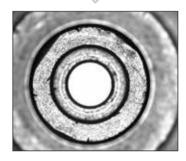
Coaxial light



Surface features are clear



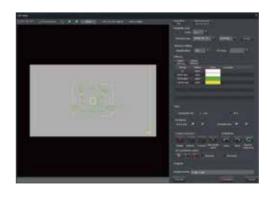
Easy to measure profile features



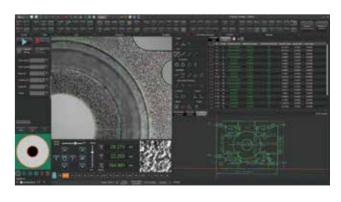
Measure diameter of blind hole

Auto batch measurement

- The program matches the coordinate system of the workpiece, automatically executes the measurement process, supports the import of CAD drawings and Gerber drawings, and coordinates system matching measurement;
- In the CNC fixed coordinate system mode, batch measurement can be performed quickly and accurately.



Import CAD drawing to build a program

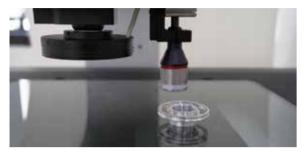


CNC batch measurement

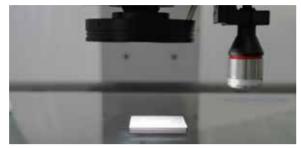


Various accessories

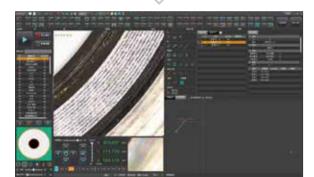
- Equips a touch probe or optical probe to measure height and flatness and realize 2.5D space measurement;
- Supports external input from digital calipers and height gauges; Supports label printers.



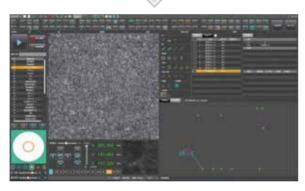
Height measurement



Flatness measurement



Height result



Flatness result

Application







Small metal parts



Machining parts



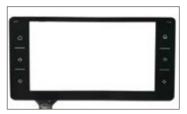
Mask board



Die cutting



Plastic injection parts



Car monitor frame



Connectors

Parameters

Model No.		CHT322A	CHT432A		
	X	300 mm	400 mm		
Travel Range	Υ	200 mm	300 mm		
nango	Z	200 mm	200 mm		
Struc	cture Type	Colu	ımn		
Base	Material	Gra	nite		
M	onitor	24" LCD(19	920×1080)		
Imag	je Sensor	1.6MP High definition co	olorful industrial camera		
Resolution	of Glass scale	0.5	μm		
	Lens	6.5X mar	iual lens		
Mag	nification	Optical Zoom: 0.7X~4.5X,	Image Zoom: 32~206X		
Liabt	Back light	Telecentric transm	ission illumination		
Light Ring Light		5 rings and 8 segments (255 levels) surface light			
	X/Y	(2.5+L/200)µm			
Accuracy*1	Χ⊥Υ	(3.0+L/200)µm			
	Z*2	(5.0+L/200)µm			
Max Speed	XY	500 mm/s			
iviax speeu	Z	1001	mm/s		
	Size	760×1220×1670 mm	860×1350×1670 mm		
W	/eight	600 kg	650 kg		
Loadin	g Capacity	25	kg		
Ро	wer	1500W	2000W		
Sensor	Option	(1)Touch probe	; (2)Laser probe		
Motion	Control	Servo co	ntrol system		
Soft	ware	Visio	nX		
In	put	AC200~2	AC200~240V, 50/60Hz		
	Environment	Temp.20°C ±2°C, Humidity 20~80%, Vibration<0.002g, Less than15Hz			

 $[\]star 1$ In the focus position, the environment temperature is +20 °C \pm 1.0 °C, and the load on the table is 5 kg or less; L is the moving range of the table in mm.

^{*2} It is mechanical accuracy, and actual accuracy depends on object surface where lens focuses.

Parameters

Model No.		CHT322U	CHT432U		
	Х	300 mm	400 mm		
Travel	Υ	200 mm	300 mm		
Range	Z	200 mm	200 mm		
Struct	ure Type	Col	umn		
Base	Material	Gra	nite		
Mo	onitor	24" LCD(1	920×1080)		
Image	e Sensor	160MP High definition o	colorful industrial camera		
Resolution	of Glass scale	0.1	lμm		
L	ens	8.3Xmoto	orized lens		
Magn	ification	Optical Zoom: 0.6~5.0X	, Image Zoom: 27~229X		
	Back light	Telecentric transn	nission illumination		
Light	Ring Light	6 rings and 8 segments (255 levels) surface light			
	Coaxial Light	LED(Optional)			
	X/Y	(2.0+L/200)µm			
Accuracy*1	Χ⊥Υ	(3.0+L/200)µm			
	Z*2	(4.5+L/200)µm			
Max Speed	XY	500	mm/s		
iviax Speed	Z	100	mm/s		
5	Size	760×1220×1670 mm	860×1350×1670 mm		
W	eight	600kg	650 kg		
Loading	g Capacity	25	skg		
Po	ower	1500W	2000W		
Senso	or Option	(1)Touch probe	; (2)Laser probe		
Motio	n Control	Servo con	trol system		
Sof	ftware	Visi	onX		
Ir	nput	AC200~24	OV, 50/60Hz		
Working I	Environment	Temp.20°C ±2°C, Humidity 20~80	%, Vibration<0.002g,Less than15Hz		

Parameters

Model No.		CHT322S	CHT432S			
	X	300 mm	400 mm			
Travel Range	Υ	200 mm	300 mm			
riango	Z	200 mm	200 mm			
5	Structure Type	Column				
	Base Material	Gran	nite			
	Monitor	24" LCD(19	20×1080)			
	Image Sensor	1.6MP High definition co	lorful industrial camera			
Resolution	n of Glass scale	0.1	ım			
	Lens	13.3X moto	rized lens			
N	lagnification*1	Optical Zoom: 0.6~8.0X,	Image Zoom: 17~380X			
	Back light	Telecentric transmi	ssion illumination			
Light	Ring Light	6 rings and 8 segments (255 levels) surfa	ace light(or RGB surface light, Optional			
	Coaxial Light	LE	D			
	X/Y	(1.8+L/2	250)µm			
Accuracy *1	Х⊥Ү	(2.2+L/250)µm				
	Z*2	(3.0+L/200)µm				
	Z measuring range	5mm				
	Scanning width *5	30mm				
3D Scanning *3	Repeatability*6	±1µm				
Scarining	Meas. Accuracy*6	±0.19	%F.S.			
	Scanning speed	10~80mm/s				
	Fly-Shooting Mode	Sup	port			
	Navigation Camera	Support				
	Sensor Option	(1)Touch probe;	(2)Laser probe			
May Coad	XY	500 n	nm/s			
Max Speed	Z	100 n	nm/s			
Ş	Size	760×1220×1670mm	860×1350×1670 mm			
W	eight	600kg	650 kg			
Loading	g Capacity	251	(g			
Po	ower	1500W	2000W			
Motio	n Control	Servo conti	rol system			
Sof	ftware	Visio	nX			
Ir	nput	AC200~240	V, 50/60Hz			
Working I	Environment	Temp.20°C ±2°C, Humidity 20~80%	, Vibration<0.002g,Less than15Hz			
lote:						



 $[\]star 1$ In the focus position, the environment temperature is +20 °C ± 1.0 °C, and the load on the table is 5 kg or less; L is the moving range of the table in mm.

^{*2} It is mechanical accuracy, and actual accuracy depends on object surface where lens focuses.

 $[\]star 1$ In the focus position, the environment temperature is +20 °C \pm 1.0 °C, and the load on the table is 5 kg or less; L is the moving range of the table (mm)

^{*2} It is mechanical accuracy, and actual accuracy depends on object surface where lens focuses.

^{*3} Optional line-scanning probe is required.

^{*4} Measuring range 5mm~40mm optional.

^{*5} Scanning width 30mm~145mm optional.

^{*6} Environment temperature is +20 °C ± 1.0 °C

Parameters

Model No.		CHT452	CHT562	CHT682		
	X	400 mm	500 mm	600 mm		
Travel Range	Υ	500 mm	600 mm	800 mm		
o l	Z	200 mm	200 mm	200 mm		
Struc	ture Type		Bridge			
Base	Material		Granite			
Мо	nitor		24" LCD(1920×1080)			
Image	Sensor	1.6MP High definition colorful industrial camera				
Resolution	of Glass scale	0.1μm				
Le	ens	8.3Xmotorized lens				
Magn	ification	Optical Zoor	m: 0.6~5.0X, Image Zo	om: 27~229X		
Back light		Telece	ntric transmission illum	ination		
Light	Ring Light	6 rings and 8 segments (255 levels) surface light				
Ligitt	Coaxial Light	LED(Optional)				
	X/Y	(2.5+L/200)µm				
Accuracy*1	Χ⊥Υ	(3.0+L/200)µm				
	Z*2	(4.5+L/200)µm				
	XY	500 mm/s				
Max Speed	Z	100 mm/s				
(Size	950×1320×1700 mm	1100×1600×1700 mm	1200×2000×1700 mm		
W	eight	1400 kg	1500 kg	2000 kg		
Loading	g Capacity		25 kg			
P	ower	2000W	2500W	2500W		
Senso	or Option	(1)To	ouch probe; (2)Laser	probe		
Motio	n Control	Servo control system				
Sof	ftware		VisionX			
li	nput		AC200~240V, 50/60H	Z		
Working	Environment	Temp.20°C ±2°C, Hu	midity 20~80%, Vibration<0	0.002g,Less than15Hz		
Note:		1				

Parameters

Model No.		CHT0810	CHT1012	CHT1215		
	X	800 mm	1000 mm	1200 mm		
Travel	Υ	1000 mm	1200 mm	1500 mm		
Range	Z	200 mm	200 mm	200 mm		
Stru	cture Type		Bridge			
Base	e Material		Granite			
Monitor 24" LCD(1920×1080)						
Imag	je Sensor	1.6MP Hig	gh definition colorful in	dustrial camera		
Resolution	of Glass scale		0.1µm			
I	Lens		8.3Xmotorized lens			
Mag	nification	Optical Zo	oom: 0.6~5.0X, Image 2	Zoom: 27~229X		
Back light		Telecentric transmission illumination				
Light	Ring Light	6 rings and 8 segments (255 levels) surface light				
Ligitt	Coaxial Light	LED(Optional)				
	X/Y	(3.0+L/200)μm (3.5+L/200)μm				
Accuracy*1	ХТА	(4.0+L/200)µm	(4.5+L/)	200)µm		
	Z* ²	(4.5+L/200)μm (4.5+L/200)μm				
M	XY	500 mm/s				
Max Speed	Z		100 mm/s			
	Size	1750×2220×1700	2150×2620×1700	2550×3220×1700		
1	Weight	2900 kg	3600 kg	4500kg		
Loadi	ng Capacity		50 kg			
	Power	2500W	2500W	2500W		
Sen	sor Option	(1)Touch probe; (2)Laser probe				
Motio	on Control	Servo control system				
S	oftware		VisionX			
li li	nput		AC200-240V, 50/60H	Z		
Working	Environment	Temp.20°C ±2°C, Hun	nidity 20~80%, Vibration<0	.002g,Less than15Hz		
Noto						



^{*1} In the focus position, the environment temperature is +20 °C ± 1.0 °C, and the load on the table is 5 kg or less; L is the moving range of the table in mm.

^{*2} It is mechanical accuracy, and actual accuracy depends on object surface where lens focuses.

^{*1} In the focus position, the environment temperature is +20 °C ± 1.0 °C, and the load on the table is 5 kg or less; L is the moving range of the table in mm.

^{*2} It is mechanical accuracy, and actual accuracy depends on object surface where lens focuses.

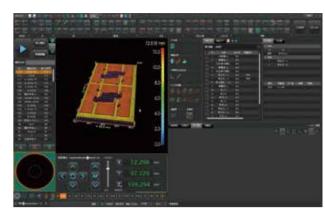
Automatic Video Measuring Machines Novator Series CHOTEST NOVATOR

Functions

- 1. Measurement tools: Extracting edge points by scanning, extracting edge points by multi-segment, extracting edge points by circle, ellipse extraction, extracting contour line by frame selection, focus point, nearest points, etc.
- 2. Measure geometric features: Point, line, circle (center coordinate, radius, diameter), arc, center, angle, distance, line width, hole site, aperture, number of holes, distance from hole to hole, hole to edge, distance from the arc center to the hole, distance from the arc center to the edge, distance from the arc high point to the other arc high point, distance from the intersection to the intersection, etc.
- 3. Construction features: Intersection, center point, extreme point, endpoint, two-point connection, parallel line, perpendicular line, tangent, bisector, center line, line segment fusion, drawing circle by radius, drawing inscribed circle among three lines, drawing inscribed circle by two lines & radius, etc.
- 4. Geometric tolerance: Straightness, roundness, contour, position, parallelism, symmetry, perpendicularity, concentricity, profile and position tolerance evaluation.

Features





Replaceable RGB surface light

Integrate 3D topography measurement

Stable moving stage, high measurement accuracy

- 1. Precision marble body, good stability and high precision.
- 2. Precision linear slide rail and servo control system, smooth and silent movement.
- 3. Three axes x/y/z programmable, realize batch inspection for complex features.

Laser scanning imaging, 3D composite measurement

- 1. Support spot-type laser probe to scan profile in height direction.
- 2. Support 3D line-scanning laser probe.
- 3. VisionX supports a variety of contour measurements and 3D spatial measurements, seamlessly connecting 2D/3D hybrid measurements.

Strobe lighting source, high speed fly-shooting

- 1. Equipped with strobe lighting source, support strobe and normal lighting modes.
- 2. Support fly-shooting measurement mode, measurement efficiency is increased by 5~10 times.
- 3. Support the stitching measurement function of the flash measuring machines.

Replaceable RGB surface light, independent lifting up and down

- 1. RGB and white light can be replaced to adapt to a variety of complex colors and material surfaces.
- 2. The surface light can be lifted independently to better observe the sample surface.
- 3. Support programmable back light, coaxial light and 6 rings and 8 segments of the surface light.

Automatic and fast batch measurement

- 1. The program matches the workpiece coordinate system and automatically executes the measurement
- 2. Support CAD drawing and Gerber drawing import.
- 3. Can execute quickly and accurate batch measurement in CNC fixed coordinate system mode.

Easy operation, hassle-free

- 1. Equipped with a large FOV navigation camera for fast workpiece positioning.
- 2. Mechanical lens anti-collision function
- 3. User-friendly operation interface, anyone can easily set and measure.

Parameters

Mo	odel No.	Novator333	Novator432	Novator562	Novator682		
	X	300 mm	400 mm	500 mm	600 mm		
Travel Range	Υ	300 mm	300 mm	600 mm	800 mm		
Ü	Z	300 mm	200 mm	200mm	200 mm		
Str	ucture Type	Bridge	Bridge	Bridge	Bridge		
Ва	se Material	Marble	Marble	Marble	Marble		
N	Monitor		24" LCD(19	20×1080)			
Ima	ge Sensor	5MI	P High definition co	orful industrial cam	nera		
Resolu	tion of Glass scale		0.1	ım			
	Lens		13.3X moto	rized lens			
Mag	nification	Optical	Zoom: 0.6X~8.0X, Ir	nage Zoom: 17X~38	0X		
I	F.O.V.		Max: 13x11mm;	Min:1.0x0.8mm			
	Back light		Telecentric transmi	ssion illumination			
Light	Ring light	6 rings and 8 seg	ments (255 levels) surfa	ace light(or RGB surfac	e light,Optional)		
	Coaxial Light		LED				
	X/Y	(1.6+L/250)µm	(1.6+L/250)µm	(1.8+L/250)µm	(2.0+L/250)µm		
Accuracy*1	ХТА	(2.0+L/250)µm	(2.0+L/250)µm	(2.2+L/200)µm	(2.5+L/200)µm		
	Z	(3.0+L/200)µm	(3.0+L/200)µm	(3.0+L/200)µm	(3.0+L/200)µm		
	Z measuring range*3	5mm					
2D	Scanning width*4	30mm					
3D Scanning* ²	Repeatability*5	±1μm					
Ü	Z Accuracy*5	±0.1%F.S.					
	Scanning speed	10~80mm/s					
Fly-Shoo	oting Mode	Support					
Navigati	ion camera	Support					
Sensor	Options		(1)Touch probe;	(2)Laser probe			
	XY	500 mm/s					
Max Speed	Z	100 mm/s					
S	iize	900×1280×1700mm	1000×1380×1700mm	1100×1820×1700mm	1200×2030×1700mm		
We	eight	800kg	1200kg	1650kg	2000kg		
Loading	Capacity	25kg	25kg	50kg	50kg		
Po	ower	2000W	2000W	2500W	2500W		
Motion	Control		Servo conti	ol system			
Sof	tware		Visio	onX			
In	iput		AC200~240)V, 50/60Hz			
Working E	Environment	Temp.20°C ±2°C	, Humidity 20~80%,	Vibration<0.002g,	Less than15Hz		
				ad on the table is Elva			

 $[\]star$ 1 In the focus position, the environment temperature is +20 °C \pm 1.0 °C, and the load on the table is 5 kg or less; L is the moving range of the table (mm)







VX3200D / VX3300D series



VX3100D / VX3030D series



VX1000 series



VX3500 / VX8500



VX4000 series



VX5000 series

^{*2} Optional line-scanning probe is required.

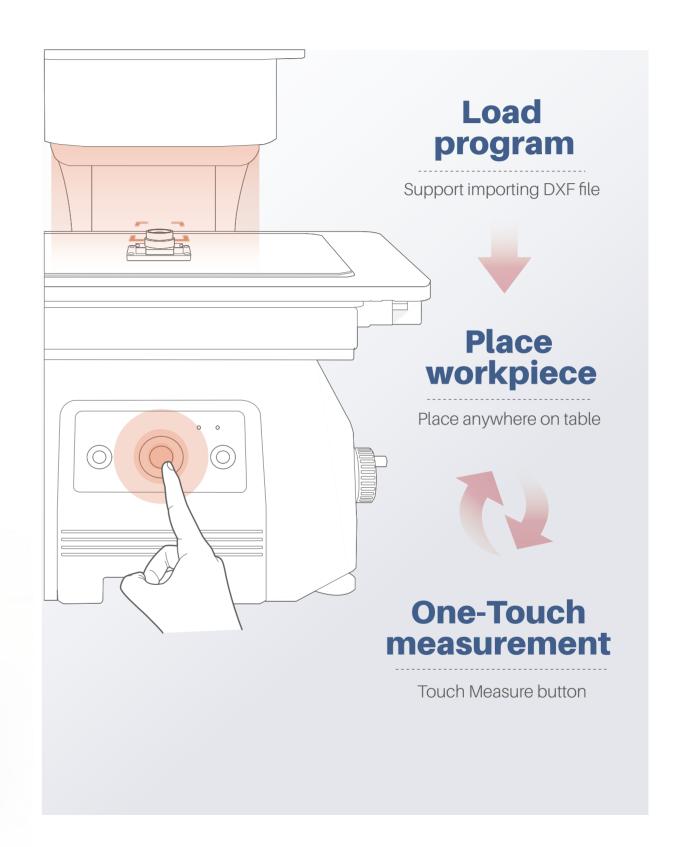
^{*3} Measuring range 5mm~40mm optional.

^{*4} Scanning width 30mm~145mm optional.

^{*5} Environment temperature is +20 °C ± 1.0 °C

Efficient measurement





Dedicated Optical Lens



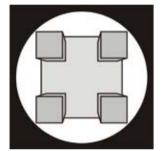




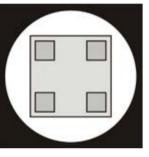
Our Dedicated lens

Clear image even if there are stages

Equipped with a high depth optical lens and automatic focusing, the flash measuring machine only needs to focus at the tested object once. Even if there are variations in height, the images remain clear.



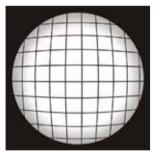
Normal Lens



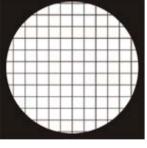
Our Dedicated lens

Always real size even if there are stages

With a double telecentric optical lens, the size of objects in the image is always real and accurate, even features that are located at edge of the field of view.



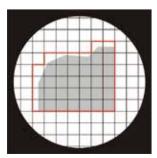
Normal Lens



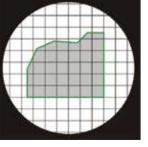
Our Dedicated lens

Zero distortion in the full field of view

Thanks to the double telecentric optical lens with high depth of field and high resolution, it is almost zero distortion of the image in the full field of view. Test result is always the same in any position of the object table.



Normal Lens



Our Dedicated lens

Sub-pixel processing of edges

With algorithms of high-order interpolation and numerical fitting, the software can perform sub-pixel processing of the edges.

Light Source

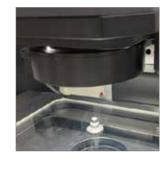
Back light

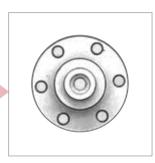


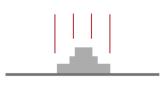




Coaxial light

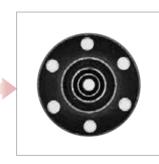


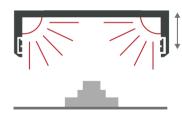




75°Ring light

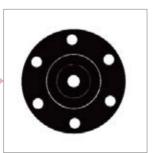






0° ring light

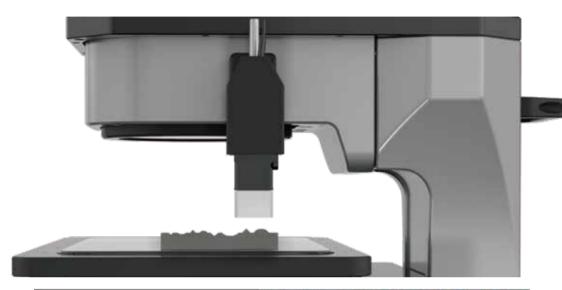


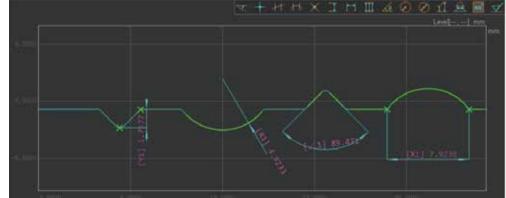




CHOTEST 37

Height probe

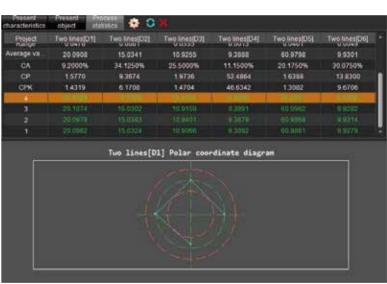




It is a white light confocal probe, and can be used to measure thickness, height difference, flatness, parallelism, etc. Moreover, this probe can scan the surface of the sample continuously.

Rotary chuck



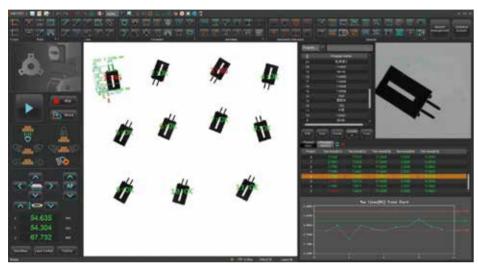


Rotary chuck can rotate 360°. It is convenient to measure the sizes in different section according to rotation angle specified by the operator. It is an ideal solution to measure all kinds of cylindrical parts, such as shaft, etc.

Software

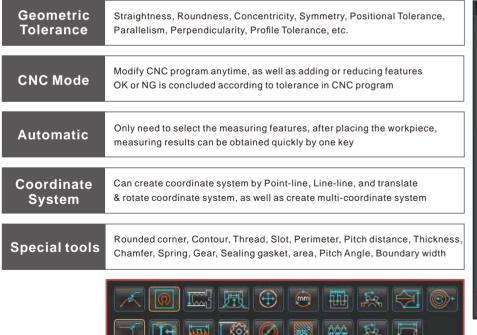
VisionX professional visual measurement software is completely independently developed by CHOTEST, and CHOTEST has independent intellectual property rights. VisionX has friendly user interface, convenient operation, powerful and practical functions, support more than 80 kinds of extraction and analysis tools, including feature extraction tool, auxiliary tool, annotation tool and special application tool, etc. Moreover, functions can be customized according to user's need, so as to improve work efficiency more effectively.

Flash Measuring Machines VX Series



Home Interface

Features

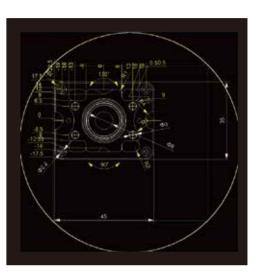




DXF Import

Measurement data can be obtained from CAD drawings. Even if the test object is not physically available, you can still create measurement programs quickly. The system can automatically assign features and dimensions from the DXF drawing to the sample, including surface dimensions





Sample

Automatically assign DXF features to the sample

Work with Robot

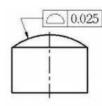
Measurement data is transmitted to the MES system of the customer via socket or HTTP protocols in real time.

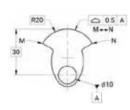
VisionX also could receive commands from the external server to load the program and begin measurement, so it is compatible with robotic arms to achieve unmanned measurements.

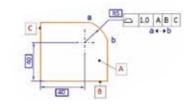


Contour Tolerance

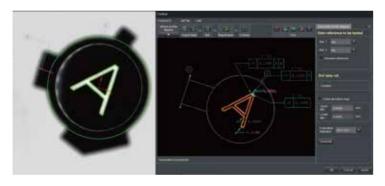
This tool has three evaluation methods: No reference (only shape error evaluation), Single reference, Multiple references.







- Multiple annotations: Multiple contour tolerance can be annotated in a single program. No need to establish a coordinate system: Just need to enter the reference in the drawing . Measurement of contour tolerance in different coordinate systems can be achieved in a single program.
- Multiple types: Evaluate the contour tolerance y scanning the entire contour; Or evaluate the profile tolerance by measuring point with specifying coordinate values.



Position Tolerance

It can measure both point position tolerance and line position tolerance. Evaluation can be performed by XY coordinates in Cartesian coordinate system or radius & angle in polar coordinate system.



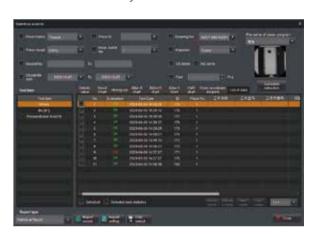
Statistical Analysis

The statistical analysis interface has the tabs of [Statistical Value], [Trend Chart], [Histogram] and [Data List]

Automatic recording and sorting

Measurement results and its main statistical information (e.g. average value, σ , 3 σ , 6 σ , Ca, Cp, Cpk etc) will be automatically recorded and saved. Operator could search records by different conditions.





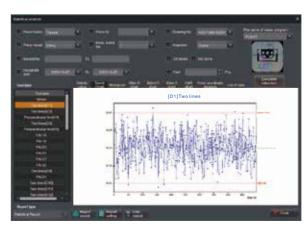
Statistic

Tabled data

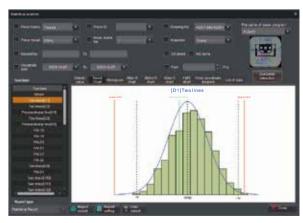
Control production process and improve product quality

The trend chart monitors the abnormalities of generating equipment and production process by regularly changing trend of measured values. Such as the monotonic and periodic changes of the measured values.

The histogram reflects the fluctuation and distribution of product quality, and transmits information about process quality, which can be used to judge and predict product quality and unqualified rate.



Trend Chart



Histogram

Application

Flash measuring machines are widely used in industry of machinery, electronics, mold, injection molding, hardware, rubber, low-voltage electrical appliances, magnetic materials, precision stamping, connectors, connectors, terminals, mobile phones, home appliances, printed circuit boards, medical equipment, watches, tools, etc.



Phone case

















Sheet metal parts Plastic injection parts Magnetic component

Cutting tools



Small metal parts





Rubber ring



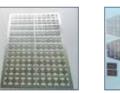


Spring

Thread, Shaft









Mask board



Rigid PCB

Connectors



Battery



Resistors



Filter mesh

Car monitor frame



Medical drill



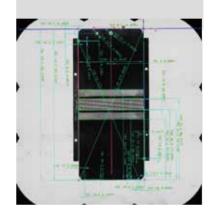




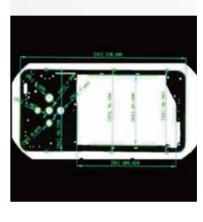
Radius gauge Thread template

Foldable Screen of Mobile Phone

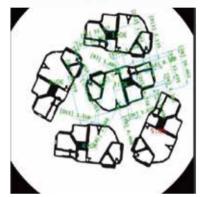






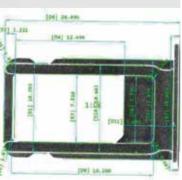






Shield slot



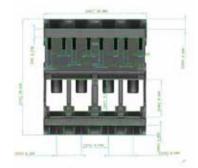


Back Cover Glass of Mobile Phone

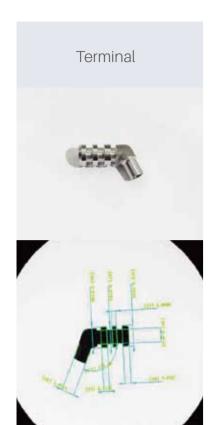






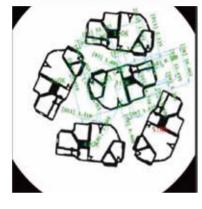


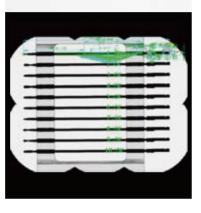
CHOTEST 45

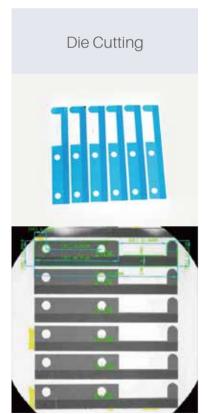
















Parameters

Model No.		No.	VX3030D	VX3100	VX3100D		
	mage S	Senor	5MP CMOS				
		Built-in	10.4"LCD(XGA: 1024x768)				
Monitor Outside		Outside		24"LCD(XGA: 1920x1080)			
Acceptance Lens				Double Telecentric Lens			
Ring light		Ring light	Four-segm	ent illumination(White Light/	Green light)		
Light		Backlight	Telecentric	c transmission illumination(G	Green Light)		
	Lai	rge Field(mm)	130x20	200x100(4 Angles R50)	200x100(4 Angles R50)		
F.O.V.	High	Precision(mm)	116x6		120x20		
	Wide	Without Stitching*1	±0.5μm	±1µm	±1 μm		
Repeatability	Field	With Stitching*2	±1 μm	±2μm	±2 μm		
of Image Meas.	High Precision	Without Stitching*1	±0.1µm		±0.5µm		
		With Stitching* 2	±0.5μm		±1.5μm		
	Wide Field	Without Stitching*1	±2 μm	±5µm	±5 μm		
Accuracy		With Stitching* 2	±(4+0.02L)µm	±(7+0.02L)µm	±(7+0.02L)µm		
Image Meas.	High Precision	Without Stitching*1	±0.7μm		±2µm		
		With Stitching* 2	±(2+0.02L) μm		±(4+0.02L) μm		
	Softv	vare	VisionX				
	Reso	ution		0.1µm			
ı	Physica	l Probe	No				
	Χ٦	Travelrange	110mm				
XY Object Table	Υ	Travelrange					
	Load	ding Capacity		2kg			
Z-	Axis Tra	avelrange		35mm(Motorized)			
	Size(L)	(WxH)	(500x280x670)mm	(500x280x670)mm	(500x280x670)mm		
	Wei	ght	31kg	30kg	31kg		
	Inp	ut		AC100~240V,50/60Hz, 2A,	300W		
Wo	rking Eı	nvironment	Temp.10°C~35°C,	Humidity 20~80%, Vibration	<0.002g, Less than15Hz		

Remark : *1 In the focus position, the environment temperature is $+20\,^{\circ}\text{C} \pm 1.0\,^{\circ}\text{C}$

 ± 2 In the focus position, the environment temperature is ± 20 °C ± 1.0 °C, and the load on the table is 1 kg or less; L is the moving range of the table (mm)

Parameters VX3200D VX3300D Model No. Image Senor 5MP CMOS 10.4"LCD(XGA: 1024x768) Built-in Monitor Outside 24"LCD(XGA: 1920x1080) Acceptance Lens Double Telecentric Lens Ring light Four-segment illumination(White Light/Green light) Light Backlight Telecentric transmission illumination(Green Light) 200x200(4 Angles R50) 300x200(4 Angles R50) Large Field(mm) F.O.V. High Precision(mm) 130x130 230x130 Resolution 0.1µm ±1µm Without Stitching* Wide Repeatability ±2µm With Stitching* 2 Without Stitching* Image Meas. $\pm 0.5 \mu m$ High With Stitching* 2 ±1.5µm Without Stitching* ±5µm Accuracy With Stitching* 2 $\pm (7+0.02L) \mu m$ of Image Meas Without Stitching* $\pm 2\mu m$ High Precision With Stitching* 2 $\pm (4+0.02L) \mu m$ Measuring Range(X*Y) 120*110mm Max Depth/Diameter(H/Φ) 1.64 Dia. of Beam Φ100μm(Φ18μm optional) Height Meas. Resolution 0.25µm (Optical Probe) Range(Z) ±2mm (Optional) Non-movement Accuracy ±2µm Range(Z) 75mm **Z** Movement Accuracy ±(6+0.01H) µm, H is Z movement height in mm X TravelRange 110mm 210mm XY Y TravelRange 110mm 110mm Object Table Loading Capacity 7.5kg Z-Axis Travel Range 75mm(Motorized) Size(LxWxH) (531x386x731)mm (531x503x731)mm Weight 49kg 75kg

Remark : ± 1 In the focus position, the environment temperature is $\pm 20\,^{\circ}\text{C} \pm 1.0\,^{\circ}\text{C}$

AC100~240V,50/60Hz, 2A, 300W

Temp.10 °C~35 °C, Humidity 20~80%, Vibration < 0.002g, Less than 15Hz

Parameters

	Model N	No.		VX8100	VX8200	VX8300	
	Image Se	enor			20MP CMOS		
Monitor		Built-	in	10.4" LCD(XGA 1024x768)			
WOTHLOT	(Outsid	de	24"LCD(XGA 1920x1080)			
А	cceptanc	e Len	S	Double Telecentric Lens			
	R	ing li	ght	Four-segment illumination(White Light/Green light)			
Light			Telecentric tr	ansmission illumination(G	Green Light)		
	Coaxial light (optional)		(optional)		LED directional light		
F.O.V.	Large Field(mm)		eld(mm)	200x100(4 Angles R50)	200x200(4 Angles R50)	300x200(4 Angles R5	
1.0.v.	High Precision(mm)		ion(mm)	130x20	130x130	230x130	
Resolution				0.1 µm			
Wide Without Stitching			±1µm				
Repeatability of	bility Field With Stitching		Stitching		±2µm		
Image Meas.			out Stitching		±0.5µm		
			Stitching		±1.5µm		
	, I light i loolololi		Field	±3µm			
Accuracy of			±(5+0.02L) μm				
Image Meas.	With	Wide	Field	±1.5µm			
Splicing*2 High pre		precision	±(3+0.02L) μm				
Horizontal	Rota	ation /	Angle	Range 360°, Resolution 0.02°			
Rotary Unit	Rota	ation S	Speed	0.2~2rev/s			
(Optional)	Max	x Dian	neter		Ф 60)mm	
	Measur	ing R	ange(X*Y)	120*110mm		120*110mm	
	Max Dep	th/Dia	meter(H/Φ)			1.64	
	Dia	a. of B	eam			Φ100μm(Φ18μm optiona	
Height Meas. (Optical Probe)	Re	esolu	tion			0.25µm	
(Optional)	. Z		Range(Z)			±2mm	
	Non-move	ement	Accuracy			±2µm	
	7.14	1	Range(Z)			75mm	
	Z Moven	nent	Accuracy			±(6+0.01H) µm, H is Z movement height in mr	
	ХТ	ravel	Range	110mm	110mm	210mm	
XY Object Table	ΥT	ravel	Range	/	110)mm	
,	Load	ing C	apacity	2kg	7.5	5kg	
Z-	Axis Trave	elRan	ge	35mm	75mm(N	lotorized)	
	Size(LxV	VxH) r	mm	500x280x670	531x386x731	531x503x731	
	Weigh	t		30kg	49kg	75kg	
	Input			AC1	00~240V,50/60Hz, 2A, 30	OW	
Wo	rking Env	ironm	nent	Temp.10 °C~35 °C,Hum	nidity 20~80%, Vibration<(0.002g Less than 15Hz	

Remark : ± 1 In the focus position, the environment temperature is $\pm 20 \,^{\circ}\text{C} \pm 1.0 \,^{\circ}\text{C}$

*2 In the focus position, the environment temperature is +20 °C ± 1.0 °C, and the load on the table is 2 kg or less; L is the moving range of the table (mm)





Input

Working Environment

^{*2} In the focus position, the environment temperature is +20 °C ± 1.0 °C, and the load on the table is 2 kg or less; L is the moving range of the table (mm)

Parameters

ı	Model No.	VX1060	VX1100	
Im	nage Senor	20MP CMOS		
	Monitor	24" LCD (XGA:1920×1080)		
Acc	eptance Lens	Double Telec	centric Lens	
1.1.	Ring light	Four-segment illumination(White Light , Manual up & dov		
Light	Backlight	Telecentric transmission	on illumination(Green Light)	
	F.O.V.	Ф60mm	Ф100mm	
Repeatal	bility of Image Meas.	±1µm	±1 µm	
Accurac	y of Image Meas.*1	±2µm	±3µm	
;	Software	VisionX		
R	Resolution	0.1µm		
Z axi	s travel range	35mm		
Loa	ding Capacity	3kg		
Si	ze(L×W×H)	500×280×670mm		
	Weight	25kg		
Input		AC100~240V, 50/60Hz, 2A, 300W		
Worki	ng Environment	Temp.10°C~35°C, Humidity 20~80%, Vibration<0.002g, Less than15Hz		

Remark: *1 In the focus position, the environment temperature is +20 °C \pm 1.0 °C

Parameters

Model No.	VX4230S	VX4230		
Image Senor	25MP CMOS	12MP CMOS		
Outside Monitor	24" LCD (XGA	:1920×1080)		
Acceptance Lens	Double Telec	centric Lens		
Transmission Illumination system	Parallel transmission ill	umination(White Light)		
Field of view	Ф230mm	200x150mm		
Depth of Field	50mm	50mm		
Working Distance	400mm			
Repeatability	±2μm			
Accuracy of Image Meas.*1	±5	ım		
Z axis travel range	65mm	100mm		
Software	Visi	onX		
Resolution	0.1	μm		
Loading Capacity	15	kg		
Size(L×W×H)	830×605×2030mm			
Weight	375kg	370kg		
Input	AC100~240V,50/60Hz, 4A, 600W			
Working Environment	Temp.10°C~35°C, Humidity 20~80%, Vibration<0.002g, Less than			
	AC100~240V,50/60Hz, 4A, 600W Temp.10°C~35°C, Humidity 20~80%, Vibration<0.002g, Less than15Hz			

Remark: *1 In the focus position, the environment temperature is $+20 \,^{\circ}\text{C} \pm 1.0 \,^{\circ}\text{C}$



Parameters

Model No.		VX5100	
Image Senor		5MP CMOS	
Outside	Monitor	24" LCD (XGA:1920×1080)	
Accepta	nce Lens	Double Telecentric Lens	
Transmission III	umination system	Telecentric transmission illumination(Green Light)	
Field	of view	Ф100mm	
Repea	tability	±2µm	
Accı	uracy *1	±5µm	
Soft	ware	VisionX	
Reso	lution	0.1µm	
Motorized XY	Rotational Speed	0.2 Revolution/s~2 Revolutions/s	
Object Table (Optional)	Diameter	Ф60mm	
(Optional)	Capacity	3kg	
Size(L	×W×H)	(736×200×325)mm	
Weight		25kg	
Inp	out	AC100~240V,50/60Hz,1.3A, 150W	
Working Er	nvironment	Temp.10 °C~35 °C, Humidity 20~80%, Vibration<0.002g, Less than15Hz	

Remark: *1 In the focus position, the environment temperature is +20 °C \pm 1.0 °C

Parameters

Model No.				VX3500	VX8500	
	Image Se	enor		5MP CMOS	20MP CMOS	
Monitor				24"LCD(XGA:1920x1080)		
,	Acceptanc	e Len	S	Double Tel	ecentric Lens	
Light	F	Ring li	ght	Four-segment illuminat	ion(White Light/Green light)	
Ligiti	E	Backli	ght	Telecentric transmission	on illumination(Green light)	
F.O.V.	La	arge F	Field	500x400mm	(4 Angles R50)	
1.0.v.	Hig	h Pre	cision	430x3	330mm	
	Resolution	on		0.1	μm	
	Wide	Witho	ut Stitching*1	±1µm	±1µm	
Repeatability of	Field	With	Stitching*2	±2µm	±2µm	
Image Meas.	High	Witho	ut Stitching*1	±0.5μm	±0.5μm	
	Precision	With	n Stitching* 2	±1.5μm	±1.5μm	
	Wide	Witho	ut Stitching*1	±5µm	±3µm	
Accuracy	Field	With	Stitching*2	±(7+0.005L)µm	±(5+0.005L)µm	
of Image Meas.	High	Witho	ut Stitching*1	±2µm	±1.5μm	
	Precision	With	n Stitching* 2	±(4+0.005L)µm	±(3+0.005L)µm	
Horizontal	Rotation Angle		Angle	Range 360°, Resolution 0.01°		
Rotary Unit	Rota	ation	Speed	0.2~2rev/s		
(optional)	Max Diameter		meter	Ф 60 mm		
	Measuri	Measuring Range(X*Y)		300*300mm		
	Max Dep	Max Depth/Diameter(H/Φ)		1.64		
	Dia. of Beam		eam	Φ100μm(Φ18μm optional)		
Height Meas. (Optical Probe)		esolu	tion	0.25µm		
(Optional)	Z		Range(Z)	±2mm		
	Non-move	ment	Accuracy	±2	μm	
	Z Moven	nant	Range(Z)	200	Omm	
	2 1010 0 011	iciit	Accuracy	±(6+0.01H)µm, H is 2	Z movement height in mm	
VV	ХТ	ravel	Range	410mm		
XY Object Table	Y T	ravel	Range	310mm		
	Load	ing Ca	apacity	20kg		
Z-	Z-Axis Travel Range			200mm(Motorized)	
	Size(LxW	/xH)		(900x134	0x1600)mm	
	Weight			950kg		
	Input			AC200~240V,50/60Hz, 10A, 2500W		
Wo	rking Envi	ronm	ent	Temp.10 °C~35 °C, Humidity 20~80%, Vibration<0.002g, Less than 15Hz		





Remark: *1 In the focus position, the environment temperature is +20 °C \pm 1.0 °C
*2 In the focus position, the environment temperature is +20 °C \pm 1.0 °C, and the load on the table is 2 kg or less; L is the moving range of the table (mm)



Description

Composite Flash Measuring Machine Hybrid series is an advanced fully automatic image measuring instrument. It adopts a hybrid architecture of an electric zoom lens and a large double-telecentric lens, offering high precision measurement for the small & complicated features by the electric zoom lens and efficient measurement for the big & easy features by the large double-telecentric lens, so it achieves an optimized combination of precise and efficient measurement.

Composite Flash Measuring Machine Hybrid series can be used in machinery, electronics, molds, injection molding, hardware, rubber, low-voltage electrical appliances, magnetic materials, precision stamping, connectors, connectors, terminals, mobile phones, home appliances, printed circuit boards, medical equipment, watches and clocks, cutting tools, measurement and testing and other fields.

Parameters

Model No.		Hybrid432 Hybrid562		Hybrid682			
	X	400 mm	500 mm	600 mm			
Travel range	Y	300 mm	600 mm	800 mm			
	Z	200 mm	200 mm	200 mm			
Stru	icture type	Column	Bridge	Bridge			
Base	e material	Marble	Marble	Marble			
N	Monitor		24" LCD (1920x1080)				
Resolutio	n of glass scale		0.1µm				
Gı	uide rail		Precision linear guide rail				
	Lens	13	.3X Electric continuous zoo	om			
	Magnification*1	Optical zoo	m: 0.6~8.0X, Image zoom	ı: 17~232X			
	Image sensor	F	ID colorful industrial camer	a			
	Single F.O.V.	1mm×1mm~12mm×12mm					
High-resolution electric zoom	Measuring range	360×310mm	410×600mm	610×800mm			
lens	Meas.accuracy (XY)*2	(1.8+L/200)µm	(2.0+L/200)µm	(2.2+L/200)µm			
	Meas.accuracy (Z)*3	(2.8+L/200)µm					
	Bottom	Telecentric transmission Illumination (Green)					
	Ring	6 rings and 8 segments light (white light)					
	Coaxial light	LED light					
	Lens Spec.	Ф100mm double telecentric lens					
	Single F.O.V.	90×90mm					
Double telecentric	Measuring range	460X330mm (4 Angles R50)	460X330mm (4 Angles R50) 480X600mm (4 Angles R50) 580X80				
wide F.O.V optical lens	Accuracy of Single F.O.V.*4		±4µm				
	Stitching Accuracy*2	(4+L/200)µm	(6+L/200)μm				
	Backlight	Telecentri	(4+L/200)μm (5+L/200)μm (6+L/200)μm Telecentric transmission Illumination (Green)				
	Ring light	4 segments illumination	(White light, 75°), directional rir	ng light (Green light, 0°)			
	XY		500 mm/s				
Max speed	Z		100 mm/s				
	Size	860×1350×1670 mm	1050×1520×1700 mm	1150×1720×1700 mm			
V	Veight	650 kg	1000 kg	1300kg			
Loading capacity		25kg	50kg	50kg			
Pow	ver supply	2000W	2500W	2500W			
Motion control			Servo control system				
S	oftware		VisionX Pro				
	Input		AC200~240V, 50/60Hz				
Working environment		Temperature 20°C±2°C, humidity 20~80%, vibration<0.002g, lower than 15HZ					

Remark: *1 Image magnification is approximate and depends on monitor size and resolution.

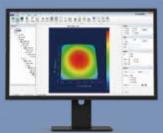
^{*2} In the focus position, the environment temperature is +20 °C ± 1.0 °C, and the load on the table is 5 kg or less; L is the moving range of the table in mm.

^{*3} It is mechanical accuracy, and actual accuracy depends on object surface where lens focuses.

 $[\]star 4$ In the focus position, the environment temperature is $+20\,^{\circ}\text{C} \pm 1.0\,^{\circ}\text{C}$.

SuperView W1 3D Optical Surface Profilometer

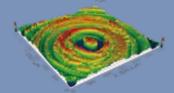
White Light Interferometry Nano 3D Surface Form and Roughness





CHOTEST

Super smooth lens



Abraded surface



Interference Lens

Different magnification lenses are selectable for various test objects with smooth or coarse surface



Vacuum **Object Table**

Vacuum Object Table is specially customized for semi-conducting wafers, so influence from feeble air flowing to test object is eliminated in measurement



Air-Bearing **Isolation System**

Built-in air bearing isolation system can isolate the vibration. Air pressure of the machine can be supplied by air compressor or inflators.



Sonic Vibration Isolation

The shell is separated from the internal motion unit, which effectively isolates the transmission of sound wave vibration.



Easy Level

Improve the re-establishment accuracy and adjust stripe width by adjusting tilt of object table



Convenient joystick

Easy to control X/Y/Z movement, speed and light source brightness; Emergency stop button

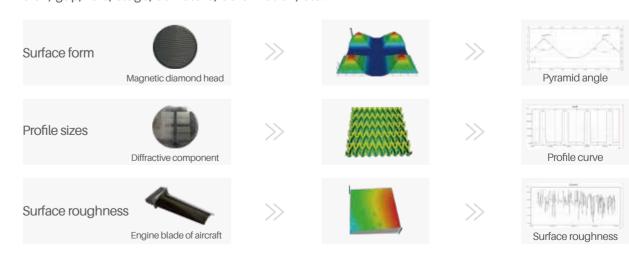
Application

It is used for measurement and analysis of surface roughness and profile of precision components from industries of semi-conductor, 3C Electronics, ultraprecise machining, optical machining, micro-nano materials, micro-electro-mechanical system.



Application Cases

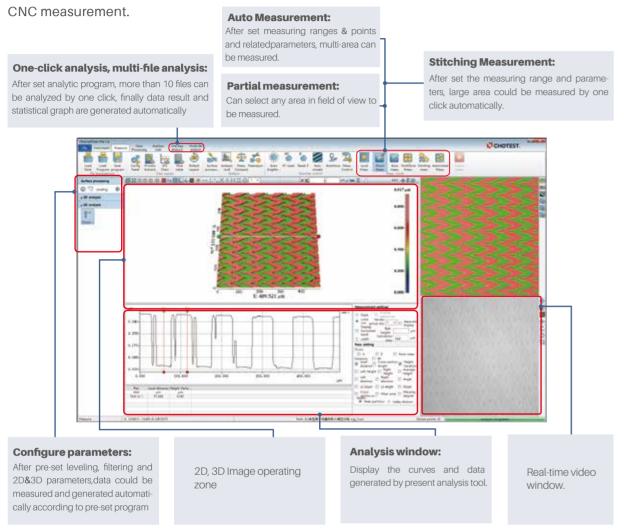
Measurement and analysis for various products, components and materials' surface form and profile characteristics, such as flatness, roughness, waviness, appearance, surface defect, abrasion, corrosion, gap, hole, stage, curvature, deformation, etc.





XtremeVision 3D Software

Integration software: Measurement and analysis are operated in the same interface; With pre-set analytic parameters, the software automatically generates measurement data, and achieves rapid



Lens Specification

Zoom ratio of lens		2.5x	5x	10x	20x	50x	100x	
Numerical hole diameter		0.075	0.13	0.3	0.4	0.55	0.7	
Optical r	resolution @55	50nm(µm)	3.7	2.1	0.92	0.69	0.5	0.4
D	Depth of focus(μm)		48.6	16.2	3.04	1.71	0.9	0.56
Worl	king distanc	e(mm)	10.3	9.3	7.4	4.7	3.4	2.0
F.O.V.	Video system	0.5x	3.84x3.84	1.92x1.92	0.96x0.96	0.48x0.48	0.192x0.192	0.096x0.096
H×V	1024x1024	0.75x	2.56x2.56	1.28x1.28	0.64x0.64	0.32x0.32	0.128x0.128	0.064x0.064
(mm)		1x	1.92x1.92	0.96x0.96	0.48x0.48	0.24x0.24	0.096x0.096	0.048x0.048

Parameters

Model No*1		SuperView W1	SuperView W1-Pro	SuperView W1-Ultra	SuperView W1-Lite	
Light source		White LED				
Vide	eo system		1024>	<1024		
Obje	ctive Lens	Stan	dard: 10X(Optional: :	2.5X, 5X, 20X, 50X, 1	00X)	
Opti	cal Zoom		Standard: 0.5X Optional: 0.375X, 0.79	5X,1X	Standard: 0.5X Optional: 0.375X, 0.75X	
Standard	Field of View		0.98×0.	.98 mm		
Lei	ns Turret	Manual 3 holes	turret(Optional: Moto	rized 5 holes turret)	Motorized 5 holes turret	
	Size	320×200mm	300×300mm	320×200mm	220×220mm	
XY Object	Travel range	140×100mm	200×200mm	140×100mm	100×100mm	
Table	Load capacity		10kg		10kg	
	Control method		Motorized		Motorized	
٦	Γilt		±5°		±3°	
	Travel Range		100mm		50mm	
Z Axis	Control method					
Z Stroke	Scanning Range	10mm				
Surface Fo	rm Repeatability* ²	0.1nm				
Roughness	RMS Repeatability*3	0.005nm			0.01nm	
Step Heigh	nt Measurementy*4	Accuracy: 0.3%; Repeatability: 0.08%(1σ)		Accuracy: 0.5% Repeatability: 0.1%(1σ)		
Scanning Spe	eed@0.1nm resolution	1.85µm/s	1.85µm/s	8μm/s	1.85µm/s	
Reflectivi	ity of Test object	0.05% ~ 100%				
1	Weight		<160 kg		50 kg	
Siz	e(L*W*H)	700×606×920mm			440×330×700mm	
	Temperature		15°C~30°C, fuctua	ation <1°C/15min		
	Humidity		5%~95% RH, no	condensation		
Operating	Vibration		VC-C oi	r better		
Environment	Software Noise Evaluation*5		3σ≤	4nm		
	Compressed Air	0.6N	1pa oil-free, water-fre	e, 6mm diameter of	hose	
	Power Supply		AC100~240V, 50	/60Hz, 4A, 300W		
	Other	1	No strong magnetic fi	eld, No corrosive ga	S	

^{*1} W1 is the standard model of 3D Optical Surface Profilometer; W1-pro has larger stage size and travel range. W1-Ultra has greatly improved the scanning speed compared to W1.



 $[\]star 2~\text{Use EPSI mode to measure Sa~0.2nm silicon wafer in the laboratory environment; Single stripe, 80 um filter for full field of view and the stripe of the stripe of$

^{*3} Measure Sa 0.2nm silicon wafer in a laboratory environment according to the ISO 25178.

^{*4} Measure standard 4.7 µm steps height block in a laboratory environment according to the ISO 5436-1:2000

^{*5} When the software noise evaluation is 4nm≤3σ≤10nm, the Roughness RMS repeatability is revised down to 0.015nm, the Step height measurement accuracy is revised down to 0.7%, and the step height measurement repeatability is revised down to 0.12%; When the software noise evaluation is 3o>10nm, the environment does not meet the requirement for usage of the equipment, and need to change the site.

SuperView W3 3D Optical Surface Profilometer

Large-scale microscopic 3D form and roughness

- Large table
- Applicable for 12" wafer
- One-key automatic measurement



Dedicated Functions for Semiconductor Field

- Measure profile trenches after laser grooving in the dicing process.
- Measure film step-height of wafer ranging from 1nm~1mm.
- Measure roughness of silicon cut sheet after grinding process, and can measure dozens of small areas to obtain the average value by one click.
- Support 6", 8" and 12" wafer measurement, and easy switch between 3 sizes of vacuum chucks by one click automatically.

Parameters

	I	Model No.			SuperView W3	
Size			(1000×900×1500) mm			
Weight			500 kg			
	Li	ight Source			White LED	
	Vi	deo System			1024×1024	
	Ob	jective Lens	1	0×,(2.5×,5×, 20×,50×,100×)	
	10	otical Zoom		0.5>	×,(0.75×, 1×,0.375×)	
	Sta	ndard F.O.V.			0.98×0.98mm	
	L	ens Turret		М	otorized 5 holes turret	
		Size			450×450mm	
XY	Object	Travel Range	300×300mm			
	Table	Load Capacity	10kg			
		Control Method	Motorized			
		Tilt	±6°Motorized			
	7 4	Travel Range			100mm	
4	Z Axis	Control Method		Motorized		
	Z- Stroke	e Scanning Range	10mm			
	Z	Resolution	0.1nm			
	Reflec	tivity of Object		0.05%~100%		
Ro	oughness	RMS Repeatability*1		0.005nm		
	p Height	Accuracy*2		0.3%		
Mea	asurement	Repeatability*2			0.08% 1σ	
Eı	nvironmer	ntal requirement				
1	Operating	g environment: No strong n	nagnetic field	4	Environmental vibration: VC-C or better	
2		emperature: 15°C~30°C fluct		5	Compressed air: 0.6Mpa oil-free, water-free	
3	Relative h	umidity: 5%~95% RH, no co	ondensation	6	Power: 600W	

^{*1} Measure Sa 0.2nm silicon wafer in a laboratory environment according to the ISO 25178

^{*2} Measure standard 4.7μm steps height block in a laboratory environment according to the ISO 5436-1:2000

SuperView W5 5-Axis **Auto 3D Optical Surface Profilometer**



Description

SuperView W5 is mainly used for high-precision measurement of surface roughness and waviness of irregular workpieces. Equipping a 5-axis object table(X/Y/Z axis, tilt & rotation), it can achieve rapid positioning throng imported 3D model. Then the measurement head can automatically scan the specified position and software obtains test data including 2D/3D topography, roughness, waviness, etc.

Parameters

Model No.		SuperView W5
Light Source		White LED
Video	System	1024×1024
Object	tive Lens	10×,20×
Field	of View	0.98×0.98 mm (10×)
	Size	400×400mm
XY Object	Travel Range	300×300mm
Table	Load Capacity	20kg
•	Control Method	Motorized
	Tilt	±90°
Doton, Ctogo	Rotation	360°
Rotary Stage	Load Capacity	10kg
	Control Method	Motorized
Z Axis	Travel Range	100mm
Z AXIS	Control Method	Motorized
Z Stroke	e Scanning Range	10 mm
Z	Resolution	0.1nm
Roughness	RMS Repeatability*1	0.005nm
Step Height	Accuracy*2	0.5%
Measurement	Repeatability*2	0.1%
Workir	ng Temperature	0~40°C, fluctuation ≤2°C/h
Working	Relative Humidity	€70%

^{*1} Measure Sa 0.2nm silicon wafer in a laboratory environment according to the ISO 25178.

^{*2} Measure standard 4.7μm steps height block in a laboratory environment according to the ISO 5436-1:2000

SuperView WX100 White Light Interferometry Probe

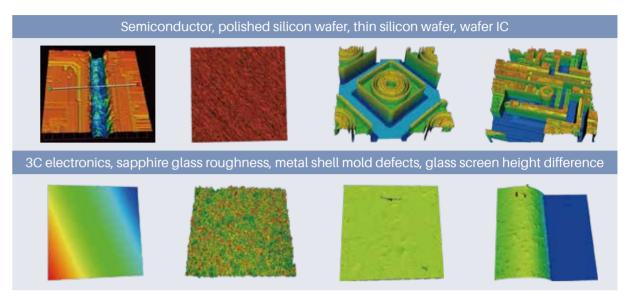
In-line roughness and 3D profile inspection



Functions

- Measurement function: it can realize high precision Z scanning of sample surface and obtain 3D image.
- Analysis function: It can obtain 2D and 3D data such as surface roughness, micro-nano-level contour size, etc.
- Programming function: Support pre-configured data processing and analysis tool steps, one-click to complete the whole process from measurement to analysis.
- Batch analysis: Data processing and analysis templates can be customized according to the customer demands, and one-click batch analysis can be realized for the same type of parameter data.

Application



Parameters

	Model No.	SuperView WX100
L	ight Source	White LED
Vi	ideo System	1024×1024
Ok	ojective Lens	10×(20×,50×)
	F.O.V	0.98×0.98mm
L	_ens Turret	Single hole
	Size	230×200×380mm
	Tilt	±2° Motorized
Z	Fravel Range	30mm
Z Sc	eanning Range	10mm(Depend on Lens)
Z	Resolution	0.1nm
Reflectiv	ity of Test Object	0.05%~100%
Roughness RMS Repeatability*1		0.01nm
Step Height	Accuracy*2	0.5%
Measurement	Repeatability*2	0.1% 1σ

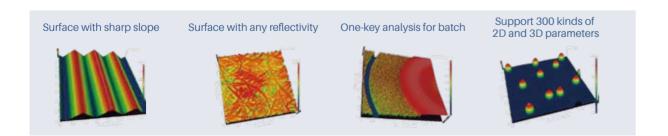
^{*1} Measure Sa 0.2nm silicon wafer in a laboratory environment according to the ISO 25178.

^{*2} Measure standard 4.7μm steps height block in a laboratory environment according to the ISO 5436-1:2000.



Description

Confocal Microscope VT6100 is dedicated for micro-nano level measurement of various precision components and material surfaces. It can measure the surface of various objects from smooth to rough, low reflectivity to high reflectivity, and the roughness, flatness, micro-geometric profile, curvature, etc. Total more than 300 kinds of 2D and 3D parameters as per four major domestic and foreign standards ISO/ASME/EUR/GBT are provided as evaluation standards.



Features

1. High precision and high repeatability

- 1) Based on the rotating confocal optical system, combined with high stability structural design and excellent 3D reconstruction algorithm, the measurement system is jointly composed to ensure thehigh measurement accuracy of the instrument.
- 2) The unique shock isolation design can reduce the vibration noise of the bottom surface, the instrument is stable and reliable in most environments, and has good measurement repeatability.

2. All-in-one operation of measurement analysis software

- 1) The measurement and analysis are operated on the same interface without switching, and the measurement data is automatically counted, realizing the function of rapid batch measurement.
- 2) The visualization window is convenient for users to observe the scanning process in real time.
- 3) Combined with the automatic measurement function of the custom analysis template, the multi-region measurement and analysis can be automatically completed.
- 4) Five functional modules of geometric analysis, roughness analysis, structural analysis, frequency analysis and functional analysis.
- 5) One-key analysis, multi-file analysis, free combination analysis items are saved as analysis templates, one-key analysis of batch samples, and data analysis and statistical chart functions are provided.
- 6) More than 300 kinds of 2D and 3D parameters can be measured according to ISO/ASME/EUR/GBT.

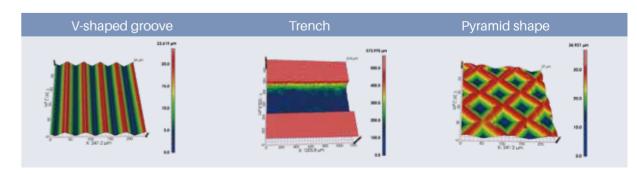
3. Precision joystick

The joystick integrated with the displacement adjustment functions in the three directions of X, Y, and Z can quickly complete the pre-measurement works such as stage translation and 2-way focusing etc.

4. Double anti-collision protection measures

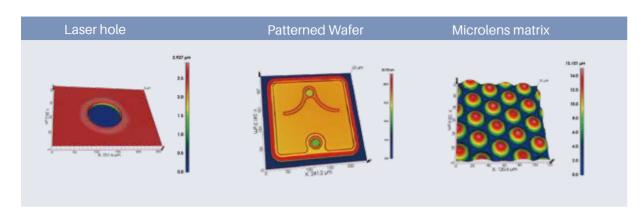
In addition to the software ZSTOP setting the lower limit of the Z-direction displacement for anti-collision protection, a mechanical and electronic sensor is designed on the Z-axis. When the lens touches the surface of the sample, the instrument automatically enters an emergency stop state to protect the instrument to the greatest extent and reduce the risk of human operation.

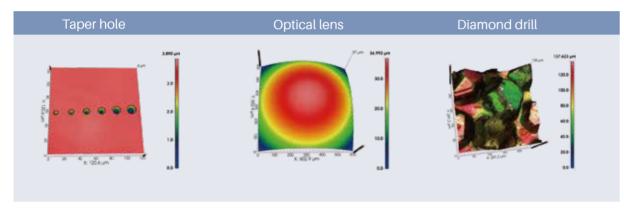
Application

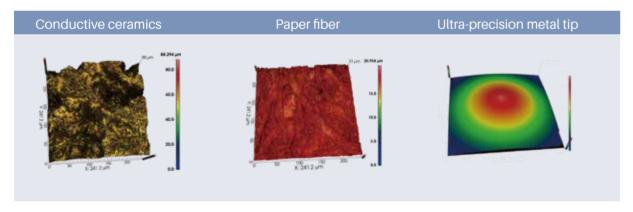


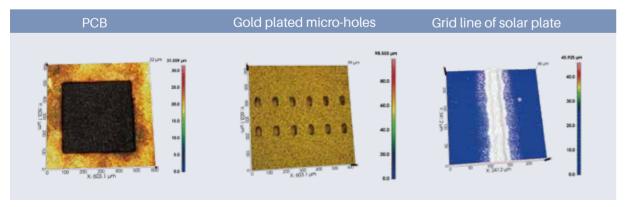


Optical Measuring Instruments Optical Measuring Instruments Confocal Microscope Confocal Microscope









Parameters

	Model No.	VT6100	VT6200	VT6300		
	Χ	100mm	200mm	300mm		
Travel Range	Υ	100mm	200mm	300mm		
9	Z	100mm	100mm	100mm		
	Size	520×380×600mm	720×580×1500mm	1000×900×1500mm		
	Weight	50kg	400kg	500kg		
	Principle	Spinniı	ng disk confocal optical	system		
0	bjective lens	50	×(Optional: 10×, 20×, 10	0×)		
F	ield of View	1	20×120 μm~1.2×1.2 mn	n		
	Repeatability(1 o)		12nm			
Step Height Measurement	Accuracy*1	± (0.2+L/100) μm				
	Display Resolution	0.5nm				
NAC Jul	Repeatability(1 o)	40nm				
Width Measurement	Accuracy*2	± 2%				
	Display Resolution	1nm				
XY Object	Load Capacity	10kg				
Table	Control Method	Motorized				
Z-Axis Stro	oke Scanning Range	10 mm				
I	Lens Turret	Motorized 5 holes turret				
L	ight Source	White LED				
	Power Supply	100~240	OV AC, 50/60Hz, 2A, Pow	/er 300W		
	Working Temp.	15℃~	√30°C, fluctuation < 2°C/	60min		
Operating	Humidity	5%	~95%RH, no condensat	ion		
Environment	Vibration		VC-C or better			
	Other		No strong magnetic field			

↓ CHOTEST 70

 $[\]star 1$ Measure standard 4.7 µm steps height block by 50× Objective lens in a laboratory environment. $\star 1$ Measure standard engraved line block by 50× Objective lens in a laboratory environment.

MX 3200 Microscopic Measuring Machine

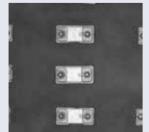


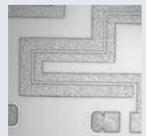
Description

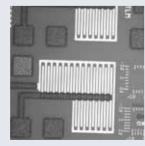
Microscopic measuring machine MX3200 achieves wide-range measurement of tiny features by combining microscopic imaging with traditional video measurement. Equipped with a motorized turret, it can measure various microscopic 2D sizes by switching different lens, including points, lines, circles and geometric tolerances, etc.

Application









Parameters

Model No.		MX3200			
Obj	ective Lens	10×	20×	50×	
Image Senor		Ir	ndustrial Colorful Camer	a	
	Monitor	2	24" LCD (XGA: 1920x108	30)	
Le	ens Turret	3 Holes Ma	anual(Optional: 5 holes i	motorized)	
Sir	ngle F.O.V.	0.98×0.98mm	0.49×0.49mm	0.196×0.196mm	
Latera	Resolution*1	2µm	1µm	0.4µm	
Accuracy*2	Single F.O.V.	±0.3µm	±0.2µm	±0.1µm	
Accuracy	Motion Axis Ex/Ey		±(2.0+0.02 L)µm		
Repeatabi	lity in Single F.O.V.*3	±0.1µm	±0.1µm	±0.05µm	
Height Meas.*4	Accuracy		$\pm (3.0 + L/100) \mu m$		
r leight ivieas.	Repeatability		±1µm		
Travel range	X		210mm		
	Υ	110mm			
	Z	75mm			
Resolution	on of Glass Scale	0.1µm			
Light	Surface Light	Coaxial light			
Ligiti	Back Light	Telecentric tr	Telecentric transmission illumination(Green Light)		
Height Meas.	Max Depth / Diameter(H/Φ)		1.64		
(Optical Probe)	Range(Z)	±2mm			
(Optional)	Accuracy	±2.0µm			
5	Software	VisionX			
Max	XY		80 mm/s		
Measurement - Speed	Z	25 mm/s			
Size(LxWxH)		531×455×761mm			
Weight		74kg			
Loading Capacity		5kg			
Power Supply		AC100~240V,50/60Hz,2A Power 300W			
Workin	g Environment	Temp.10°C~35°C, Hum	idity 20~80%, Vibration<	:0.002g, Less than15Hz	

 $[\]star 1$ In the focus position, measure resolution panel when the environment temperature is $\pm 20\,^{\circ}\text{C} \pm 1.0\,^{\circ}\text{C}$.

CHOTEST 71

 $[\]star 2$ In the focus position, measure Micro-Nano standard specimen when the environment temperature is ± 20 °C ± 1.0 °C.

^{*3} In the focus position, measure Micro-Nano standard specimen when the environment temperature is +20 °C ± 1.0 °C.

^{*4} It is the Z-axis mechanical accuracy, and the accuracy of actual height measurement by focusing depends on the surface of the workpiece.



Laser Tracker GTS Series

Large-scale space measurement

Integrated Measurement Head

Powerful CPU processing capability, compact control system are built into the laser head, and this integrated design greatly reduces the product volume and number of connection cables.

Automatic Locking

The camera will automatically search for the SMR in a certain area when the beam interrupts, and automatically lock the SMR after find it. The whole process does not require human operation.

HIADM

Absolute Distance Meter(ADM) and laser interferometer(IFM) fusion technology (HiADM) ensures excellent measurement accuracy and realizes Re-establish Beam Interruptions.

Integrated **Environmental Weather Station**

The integrated environmental weather station automatically monitors the environmental meteorological parameters, and compensates the influence of temperature, air pressure and humidity in real time.



The instrument and computer can communicate with each other through hardware trigger, wired network or WIFI. The max measurement data output speed is 1000 points/second.



Portable

The laser head and accessories are packed well in portable boxes, making it easy to transport between different work sites.



IP54 Protection

IP54 protection level ensures that the host is protected from dust and other pollutants, and has strong environmental applicability.



Steady Tripod

The stable triangular support system avoids the loss of accuracy caused by environmental vibrations.

6D Attitude Probe iProbe

- Sensing fusion technology of machine vision and gravity alignment to measure spatial attitude.
- It can measuregeometric structures of holes' internal and hidden features.
- Dual-probe design, more efficient when measuring complex features.
- Wireless transmission, easy to carry.

6D Attitude Smart Sensor iTracker

- The attitude sensor automatically follows and locks the laser beam, which has high measurement flexibility.
- The pitch angle and yaw angle are not limited by the receiving angle of the
- Simple interface connection, easy to install on machine tools or robots, high repeatability and precision.
- Dedicated band laser beam and filter design, not sensitive to ambient light
- The highest sampling speed is 200 points/second.



Application









Train Assembly

Nuclear Generator Assembly









Wind-Driven Generator Assembly

Rocket Assembly

Hydroelectric Generator Assembly

Robot Arm Calibration









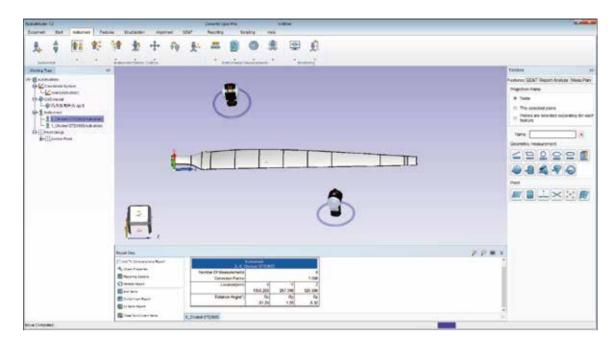
TBM Assembly

Car Assembly

Large Weapon Assembly

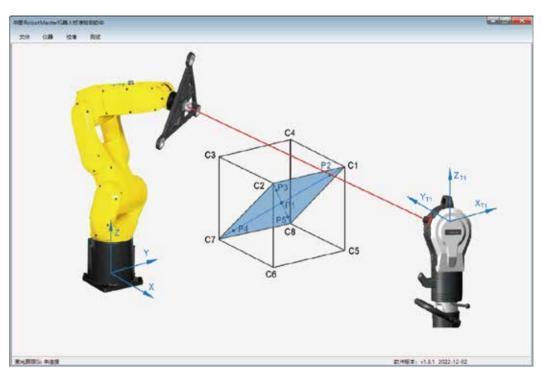
Large Machine tool Calibration

Spatial Measurement Software Spatial Master



- Traceability, faithfully record the measurement information of all measurement points of all instruments.
- Rich geometry construction methods and accurate fitting algorithms, certified by Gauss and Chebyshev double PTB.
- Multiple registration and alignment methods such as optimal fitting, sequential registration, and comprehensive alignment.
- Provides powerful analysis functions, geometric relationship measurement functions, including professional GD &T evaluation.
- The convenient monitoring function can provide efficient assembly and adjustment services for the actual production assembly process.
- Self-controllable, visible and available report format, meeting various report format requirements.
- Automatic measurement, In-line measurement, Guide point measurement, Batch point measurement functions improve measurement efficiency.
- Support multi-station simultaneous measurement, and can carry out unified spatial measurement and analysis of multi-tracker multilateral method.
- Provide SDK interface, support user independent programming.

■ Robot Calibration Software Robot Master



Robot Master Software

The RobotMaster kit provides an absolute position accuracy calibration and performance test for industrial robots. RobotMaster supports not only enhanced solutions based on 6D attitude smart sensors, but also supports economic solutions based on SMR.

■ Robot Calibration Software

According to the DH parameters of the robot, the robot calibration mathematical model is established, and the robot zero position calibration, the robot DH parameter calibration, and the robot TCP center point accuracy calibration are performed. Without changing any structure and hardware size of the existing robot, the absolute pose accuracy of the robot can be effectively improved through the robot calibration software.

■ Robot performance testing software

According to the ISO 9283 industrial robot performance specification and its experimental method, the robot performance test is completed. The test content includes: robot pose accuracy, pose repeatability, multi-directional pose accuracy change, distance accuracy, distance repeatability, position stabilization time, position overshoot, pose characteristic drift, interchangeability, trajectory accuracy, trajectory repeatability, corner deviation, trajectory velocity characteristics, static compliance, etc.

Optical Measuring Laser Tracker Instruments

Laser Tracker

■ GTS3000 Series Parameters

Model No.		GTS3300	GTS3600	GTS3800
	Head Size	220×280×495mm	220×280×495mm	220×280×495mm
	Head Weight	21.0Kg	21.3Kg	21.3Kg
Basic Spec.	Controller		Integrated	
	Laser Generator*1	6	333nm, 1mW/CW Class	2
	Support 6D		No	
	Protection Level		IP54	
	Max Distance(Radius)	30m	60m	80m
Measuring Range	Horizontal	±360°	±360°	±360°
Range	Vertical	-145°~+145°	-145°~+145°	-145°~+145°
	Volumetric Accuracy	15μm+6μm/m	15μm+6μm/m	15μm+6μm/m
Accuracy*2	IFM Accuracy	0.5μm/m	0.5μm/m	0.5µm/m
	ADM Accuracy	10μm(Entire range)	10μm(Entire range)	10μm(Entire range)
	Level Accuracy	2.0"	2.0"	2.0"
Data	Output Rate	1000points/sec.	1000points/sec.	1000points/sec.
Communication	Cable Connection		TCP/IP(Cat5)	
Communication	Wireless Connection	WLAN(IEEE 802.11N)		
F	Operating Temperature	0°C~40°C		
Environmental	Altitude	-500~+3500m		
	Relative Humidity		9	
Power Supply		220±10%VAC, 50/60Hz, 4A, 220W		

 $[\]star 1$ According to IEC60825-1(2014-5), it meets the radiation performance standard.

Parameters of 6D Attitude Probe

	6D Attitude Probe iProbe				
Measuring Range	Max Range(Radius)	30m			
Dagia Cross	Weight*1	0.68kg			
Basic Spec.	Size*2	93×90×178mm			
Accuracy	Spatial Accuracy*3	60μm+6μm/m			
	Ball Diameter	3mm、6mm			
Measuring Arm	Arm Material	Li-ion battery			
	Arm length	40mm, 100mm, 200mm, 400mm			
On many uniquetion	Max Transmission Speed	100Hz			
Communication	Connection Type	WIFI			
Power supply	Туре	Li-ion battery			
FOWER Supply	Working Duration	≥8 hours			

^{*1} Includes battery and 100mm measuring arm;

GTS6000 Series Parameters

Model No.		GTS6300	GTS6600	GTS6800		
	Head Size	220×280×495mm	220×280×495mm	220×280×495mm		
	Head Weight	21.0Kg	21.3Kg	21.3Kg		
Basic Spec.	Controller	Integrated				
-	Laser Generator*1	633nm, 1mW/CW Class 2				
	Support 6D		Yes			
	Protection Level		IP54			
	Max Distance(Radius)	30m	60m	80m		
Measuring	Horizontal	±360°	±360°	±360°		
Range	Vertical	-145°~+145°	-145°~+145°	-145°~+145°		
	Volumetric Accuracy	15μm+6μm/m	15μm+6μm/m	15μm+6μm/m		
Accuracy*2	IFM Accuracy	0.5µm/m	0.5μm/m	0.5μm/m		
	ADM Accuracy	10μm(Entire range)	10μm(Entire range)	10μm(Entire range)		
	Level Accuracy	2.0"	2.0"	2.0"		
Data	Output Rate	1000points/sec.	1000points/sec.	1000points/sec.		
Communication	Cable Connection		TCP/IP(Cat5)			
Communication	Wireless Connection	WLAN(IEEE 802.11N)				
Environmental -	Operating Temperature	0°C~40°C				
	Altitude	-500~+3500m				
	Relative Humidity	0~95%. non-condensing				
Power Supply		220±10%VAC, 50/60Hz, 4A, 220W				

 $[\]star 1$ According to IEC60825-1(2014-5), it meets the radiation performance standard.

Parameters of 6D Attitude Sensor

	6D Attitude Sensor iTracker				
Measuring Range	Max Range(Radius)	30m			
D	Weight	1.32kg			
Basic Spec.	Size	105×98×168mm			
	Pitch	-55°~+60°			
Measuring Range	Yaw	±180°			
	Roll	±360°			
	Attitude Angular Accuracy	0.03°			
Accuracy	Repeatability	0.005°			
Communication	Max Transmission Speed	200Hz			
	Connection Type	30m cable			
Power supply		From laser tracker			

^{*2} The accuracy index is the maximum permissable error (MPE), using the standard 1.5"SMR, excluding the influence of air temperature variations.

^{*2} Does not include measuring arm;

^{*3} Uses 100mm measuring arm.

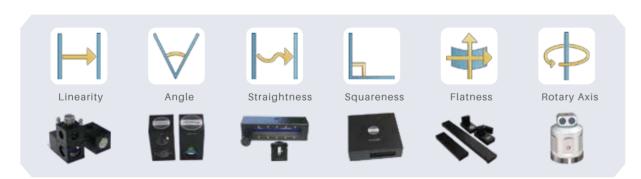
^{*2} The accuracy index is the maximum permissable error (MPE), using the standard 1.5"SMR, excluding the influence of air temperature variations.

Laser Interferometer SJ6000

Calibration of Guide Rail



Prism Modules



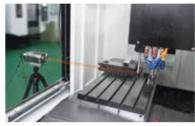
Laser interferometer is recognized as a high precision, high sensitive measuring method by applying light wavelength as criterion, and is widely used in high-end manufacturing industries.

Laser interferometer SJ6000 insists of high-frequency Helium-Neon laser generator from an USA supplier, high-precision environmental compensation modules, high-precision laser interference signal processing system, high-performance computer control system. By applying with thermal frequency stabilization technology of laser dual-longitudinal mode and geometric parameters interference optical path design, SJ6000 can output long-term stable and high-precision(0.05ppm) laser quickly(about 6 minutes) which has powerful anti-interference performance. With different prism modules, it can measure linearity, angle, straightness, flatness and perpendicularity, besides it can also analyze dynamic characteristics.

Functions

- 1. Calibrate motion accuracy of guide rail quickly and accurately.
- 2. Measure and analyze many kinds of dynamic parameters, such as displacement, velocity, acceleration and amplitude frequency.
- 3. Built-in variety of general standards of machine tools.

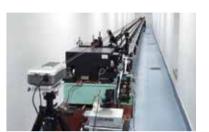
Application







Linear meas, of stage module



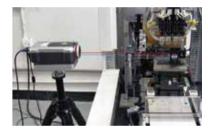
Lab length reference



Linear meas. of machine tool



Angle meas. of stage module



Angle meas. of DC motor



Parallelism meas. of two guide rails



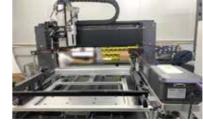
Straightness meas. of equipment



Flatness meas. of Granite table



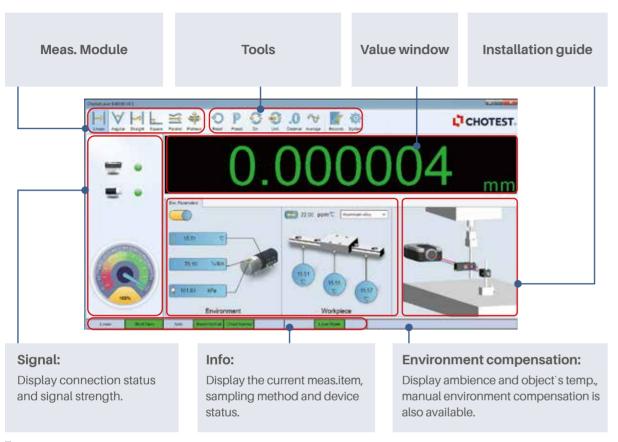
Perpendicularity meas. of CMM





Perpendicularity meas, of equipment Twin guide rails meas, of equipment

Software



Dynamic Measurement Application

Time based

Motion performance evaluation

- * Control parameter test and setting of motion controller PID.
- * Stability test and evaluation after high-speed motion.
- * Small steps test of high-performance motion controller.

Vibration monitoring

* Scanning application:

Applied for the situation when positioning accuracy is not important but constant speed is critical for high quality imaging.

* Machine tool applications:

Applied for the situation when slow and smooth contour movement of cutting tool is critical for high quality machning.

Vibration frequency analysis

- * Vibration frequency analysis of the measured object
- * FFT fast Fourier transform analysis

Distance based

In distance-based dynamic measurement, laser interferometer SJ6000 "flies" along the axis, that means SJ6000 samples data at designated points without stopping.

Pulse Trigger Mode

Pulse trigger CT70 is compatible with glass scales, encoders and controllers. Equipped with Pulse trigger CT70, laser interferometer SJ6000 can sample data in pulse trigger mode. Even if the axis does not stop, laser interferometer SJ6000 could sample data at designated points or continuously sample data.



Parameters

System parameters:

- 1. Measuring method: single frequency
- 2. Laser frequency accuracy: 0.05ppm
- 3. Dynamic capture rate: 50kHz
- 4. Warm-up time: about 6 min
- 5. Operating temperature: (0~40)°C
- 6. Environment temperature: (0~40)°C, humidity: 0-95%
- 7. Storage temperature: -20°C~70°C

Environmental sensors:

- 1. Atmospheric temperature sensor: ±0.1°C(0~40)°C, resolution: 0.01°C
- 2. Material temperature sensor: ±0.1°C (0~55)°C, resolution: 0.01°C
- 3. Atmospheric humidity sensor: ±6%RH (0~95%)
- 4. Atmospheric pressure sensor: ±0.1kPa (65~115)kPa

Linear measurement:

- 1. Measuring range: (0~80)m
- 2. Measuring accuracy: 0.5ppm (0~40)°C
- 3. Measuring resolution: 1nm
- 4. Maximum measuring speed: 4m/s

Angle measurement:

- 1. Axial range: (0~15)m
- 2. Measuring range: ±10°
- 3. Measuring accuracy: ±(0.02%R+0.1+0.24M)" (R is indicating value, unit: "; M is measured length in meters)
- 4. Measuring resolution: 0.01"

Flatness measurement:

- 1. Axial range: (0~15) m
- 2. Flatness measuring range: ±1.5 mm
- 3. Measuring accuracy: ±(0.2%R+0.02M²) um (R is indicating value in um; M is measured length in meters)
- 4. Substrate size: 180mm adjustable, 360mm adjustable
- 5. Measuring resolution: 0.1 um

Straightness measurement:

Item	Axis range	Measuring range	Accuracy	Resolution
Short straightness	(0.1~4)m	±3.0mm	±(0.5+0.25%R+0.15M ²)μm	0.01μm
Long straightness	(1~20)m	±3.0mm	±(5.0+2.5%R+0.015M ²)μm	0.1μm

Note: R is indicating value in um; M is measured length in meters

Squareness measurement:

Item	Axis range	Measuring range	Accuracy	Resolution
Short straightness	(0.1~3)m	±3/M mm/m	±(2.5+0.25%R+0.8M)μm/m	0.01μm/m
Long straightness	(1~15)m	±3/M mm/m	±(2.5+2.5%R+0.08M)μm/m	0.01μm/m

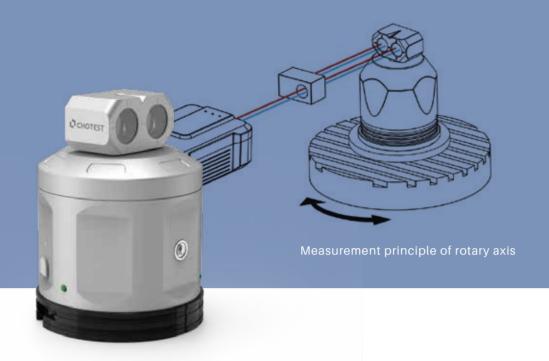
Note: R is indicating value in um; M is measured length in meters

Rotary axis measurement:

- 1. Measuring range of angle: 0~360°
- 2. Max axis rotation speed: 10rpm
- 3. Pitch accuracy of precision turntable: ±1"
- 4. Resolution: 0.01'

CHOTEST 81

Rotary Axis Calibrator WR 50



■ Measurement Principle

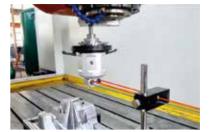
Equipped with Rotary axis calibrator WR50 and Angle prism, Laser interferometer SJ6000 is capable to calibrate rotary axis 0~360°. Rotary axis calibrator WR50 is intalled to the rotary axis as an angle master.

Parameters

Model No.	WR50	Weight	1.9kg
Measuring range	(0~360)°	Height	148mm
Measuring accuracy	±1"	Diameter	112mm
Resolution	0.01"	Communication type	Bluetooth
Max axis rotation speed	10rpm	Power supply	Li-battery
Max tracking speed	2rpm		

Application



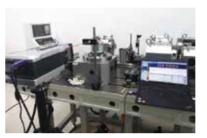


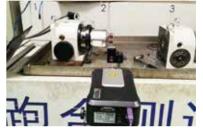


Rotary axis measurement of CNC

Electric spindle measurement of CNC

Swing axis measurement of CNC



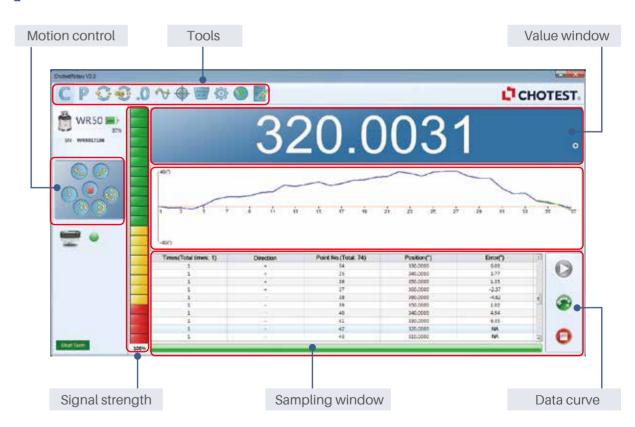




Angle measurement of CNC index plate Angle measurement of turntable

Angle measurement of CNC turntable

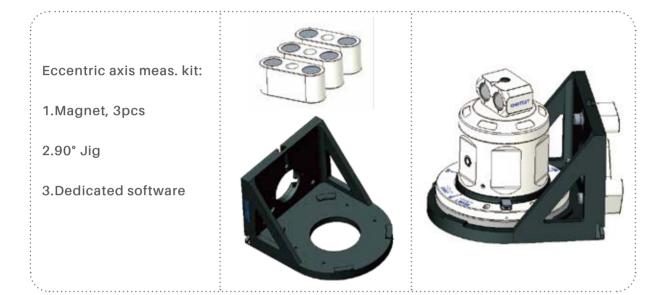
Software



Eccentric Axis Measurement

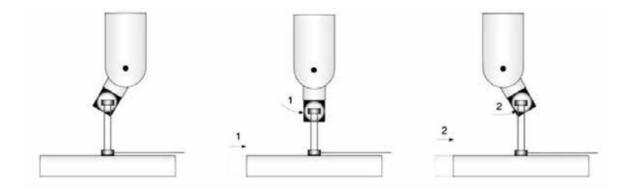
Equipped with angle prism, precision turntable WR50, dedicated jig and dedicated software, SJ6000 is capable to calibrate eccentric axis rotation accuracy.

Rotary Axis Calibrator

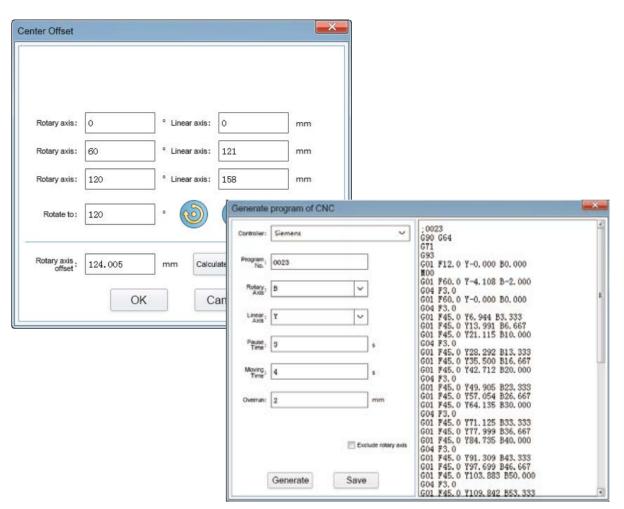


Measurement Principle

The measurement principle is to use the synchronous movement of the object table and the main spindle, as shown in the figure below. It is important to make sure that angle prism should be always aligned with WR50.



Software Settings



Application







Eccentric axis measurement

Wireless Ballbar MT21

Fast Diagnosis for Machine Tools



Feature

Simple, Fast

The measurement software with guided operation can generate the machine running program automatically. With simple setting, the round track test on three orthogonal planes can be completed in 10~15 minutes.

Powerful Function

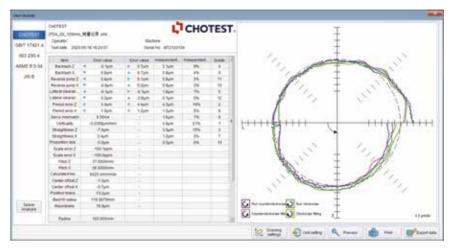
Comprehensive diagnosis report provides a full and professional assessment of machine performance. Taking 360 degree measurement at the XY plane as an example, it can analyze: backlash X, backlash Y, reverse jump X, reverse jump Y, lateral gap X, lateral gap Y, period error X, period error Y, servo Mismatch, perpendicularity, straightness X, straightness Y, proportional mismatch, scale error X, scale error Y, thread pitch X, thread pitch Y, feed rate, center offset X, center offset Y, position tolerance, the best fitting radius, roundness.

Wireless

Data is transmitted to the laptop computer via Bluetooth in real time.

Software

MT21 software with guided operation can implement the round track test on three orthogonal planes quickly and simply. After measurement, software calculates the overall measurement values (roundness, roundness deviation) of the positional accuracy automatically, then generates the analysis report with the graphic format according to GB17421-4, ISO230-4. MT21 achieves the real spatial diagnosis for machine tools.



Error Analysis Report

Parameters

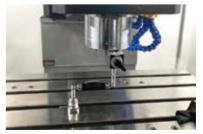
Communication: Bluetooth(Typical 10m)					
Power supply: Li-battery					
Resolution: 0.1µm					
Measuring accuracy: ±(0.7+0.3%L)μm					
Measuring range: ±1.0mm					
Sensor range: ±2.0mm					
Sample rate: 1000Hz					
Working Temperature: (0~40)°C					
Size: 120×26×21mm					

Configuration

1. MT21 Wireless Ballbar	1pc			
2. Master gauge	1pc			
3. Offset setting ball	1pc			
4. Centric holder	1pc			
5. Tool cup	1pc			
6. Extension bar 50, 100, 150mm 1pc	of each			
7. Software				
8. Portable suitcase				
9. User Manual				

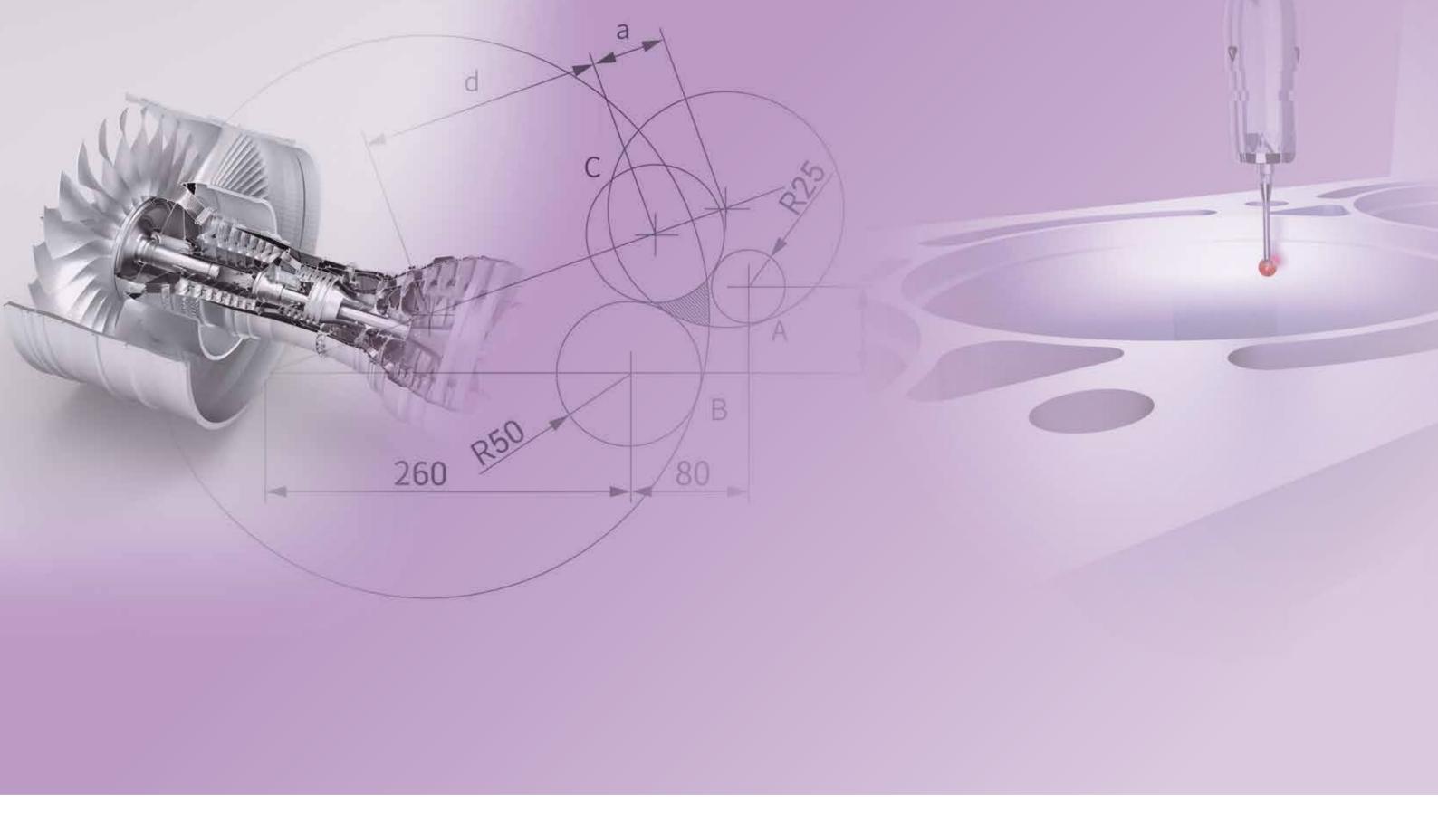
Application







Roundness inspection of machine tools



Contact Measurement Instruments

SJ5780 Series **Intelligent Profilometer**

Two-Sided Scanning Dedicated for Threaded workpieces



Application



Coaxiality of lead screw



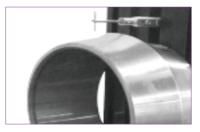
Thread gauge



Trapezoidal lead screw



Ballscrew



Cylindrical workpiece



Features

1. Two-sided profile scanning function

It obtains profile of object by scanning the surface with T-shaped stylus, then software can calculate the 2D sizes and GD & T based on the profile.

2. Thread scanning function

It can scan ordinary thread ring/plug gauges, tapered thread ring/plug gauges, plain ring/plug gauges, trapezoidal thread, sawtooth thread, multi-head threaded workpieces, lead screws, etc. Then the software can analyze their comprehensive parameters such as internal and external diameter, profile parameters, etc.

Model No.		SJ5780-200	SJ5780-300	SJ5780-400		
	Measuring	Х	0~235mm	0~325mm	0~400mm	
	Range	Z	0~235mm	0~325mm	0~400mm	
	Min	Resolution		0.001µm		
Basic Spec.	Scan	ning Speed		0.1~2mm/s		
	Meas	uring Force		10~150mN		
	M	ax Slope	1	Uphill 78°, downhill 87	0	
	Y Direction	on Object Table	Travel range 25mm, O	verall height 85mm(Mo	torized table is optional	
	Thread M	easuring Range	Interal: M3~M200, Ext	ernal: M3~M200(Detern	nined by optional jigs)	
Thread Meas.	Accuracy(M	aj., Pit., Min. Diamter)	≤±(4+L/10	0) μ m, L is measured le	ngth in mm	
	Accuracy	y(Thread Pitch)	≤±(1+L/10	≤±(1+L/100) µ m, L is measured length in mm		
	Diameter Measuring Range		Internal: φ3~φ200, External: φ3~φ200(Determined by optional jigs)			
Contour Meas.	Diameter Measuring Accuracy		≤±(3+L/100) µ m, L is measured length in mm			
	Profile Degree Accuracy		≤±(2 +L/100) µ m, L is measured length in mm			
	Roughness Parameters		R Roughness: Rp,Rv,Rz,Rc,Rt,Ra,Rq,Rsk,Rku,RSm,RPc,Rdq,Rdc,Rmr,Rmax,Rpm,tp,Htp,Pc,Rda,Ry,Sm,S,Rpc,RzJ;			
			Key Roughness: Rk, Rpk, Rvk, Rpkx, Rvkx, Mr1, Mr2, A1, A2, Vo; Profile: Pa, Pq, Pt, Pz, Pp, Pv, PSm, Psk, Pku, Pdq, Pdc, Pc, PPc, Pmr, Rad, PzJ, Pmax;			
			Wavinessof Profile: Wa,Wq,Wt,Wz,Wp,Wv,WSm,Wsk,Wku,Wdq,Wdc,Wmr,Wpc,Wc;			
Roughness			Motif: R,AR,W,AW,Rx,Wx,Wte;			
Meas.	Ra Mea	asuring Range	Ra0.012μm~Ra12.5μm			
(Optional)	А	ccuracy	5%			
		Filter	2RC filtering, Gaussian filtering and Zero phase filtering			
	Samp	oling Length	0.008, 0.08, 0.25, 0.8, 2.5, 8.0, 25mm			
	Evalu	ation Length	Automatic calculation			
	Cutoff	f Wavelength	0.25/0.8/2.5(mm) or User-defined cut-off			
	Size(L×W	/×H)	1200×500×980mm	1200×500×1180mm	1200×500×1180mm	
Weight		100kg	200kg	200kg		



SJ5720-OPT Series **Profilometers for Optics Surface**

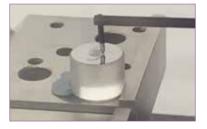


SJ5720-OPT100

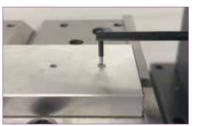
SJ5720-OPT200

Application

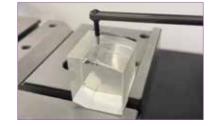




Intraocular lens mold



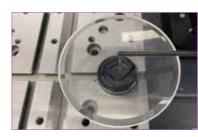
Vehicle Lens



Infrared lens



Optical mold



Lens

Description

The SJ5720-OPT series is a capable to measure both surface roughness and profile after once scanning. Moreover, there is a dedicated software module for measurement and analysis of large aspheric surface, so this series is an ideal measurement solution for the optical lens industry.

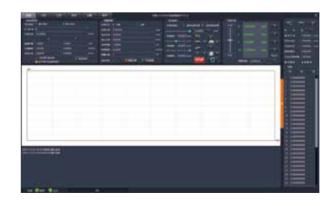
It can also be used for profile and roughness measurement for large curved surface, such as bearings, artificial joints, precision molds, gears, blades, etc. Consequently, it is widely used in precision machining, automobiles, bearings, machine tools, molds, precision hardware and other industries.

Features

- 1. Evaluate profile and roughness parameters at the same time after once scanning
- 2. High precision, high stability, and high repeatability
- 3. Aspheric optical software module
- 4. Intelligent management and advanced software analysis system
- 5. Intelligent protection system during scanning
- 6. Flexible manual control
- 7. High stability vibration isolation system

Software

- Professional aspheric surface measurement software can analyze all aspheric surface.
- parameters. There are some self-checking parameters in the software, so the correctness of the input formula can be determined by self-checking.





Aspheric surface measurement interface

Parameters

Model No.			SJ5720-OPT100	
		X	0~100mm	
	Measuring	Z	0~300mm	
	Range	Z1	±6mm (Optional: ±12mm)	
	Res	olution	0.001um	
		Z1* ¹	≤± (0.5+0.03 H) μm (H, mm)	
	Acquirect	Pt*2	Pt≤0.2μm	
Contour	Accuracy	Standard Ball*3	≤± (1+R/20) μm (R, mm)	
Measurement		Angle*4	≤±1′	
	Moving	X	0~20mm/s	
	Speed	Z	0~20mm/s	
	Scann	ning Speed	0.05~5mm/s	
	X Stra	aightness*5	≤0.15µm/100mm	
	Measu	uring Force	0.5mN, 0.75mN, 1mN, 2mN, 3mN(Adjustable)	
	Ra Masurement Range		Ra0.012μm~Ra12.5μm	
	Accuracy*6		Ra0.012μm ~ Ra3 . 2 μm: ≤±(3nm+2.0%A),A(Ra)μm Ra3.201μm ~ Ra12.5μm : ≤±(3nm+3.5%A),A(Ra)μm	
	Repeatability (1δ)* ⁷		1δ≤1nm	
	Measurer	ment Residual*8	Rq≤3nm	
	Roughness Parameters		R Roughness: Rp,Rv,Rz,Rc,Rt,Ra,Rq,Rsk,Rku,RSm,RPc,Rdq,Rdc,Rmr,Rmax,Rpm,tp,Htp,Pc,Rda,Ry,Sm,S,Rpc,RzJ;	
			Key Roughness: Rk, Rpk, Rvk, Rpkx, Rvkx, Mr1, Mr2, A1, A2, Vo;	
Roughness Measurement			Profile: Pa,Pq,Pt,Pz,Pp,Pv,PSm,Psk,Pku,Pdq,Pdc,Pc,PPc,Pmr,Rad,PzJ,Pmax; Waviness of Profile: Wa,Wq,Wt,Wz,Wp,Wv,WSm,Wsk,Wku,Wdq,Wdc,Wmr,Wpc,Wc Motif: R,AR,W,AW,Rx,Wx,Wte; Standards:	
			GB/T 3505-2009,ISO 4287:1997,ISO13565-2:1996,ASME B46.1-2002, DIN EN ISO 4287:2010,JIS B 0601:2013,JIS B 0601-1994, JIS B 0601-1982,ISO 1302:2002	
	Aspheric Masurement Parameters		Micro profile parameters: Pt, Pa, Fig;Inclination parameters: Smx, Smn; Horizontal axis angle parameter: Tilt; Distance parameters between the optical axis and the contour: Xp, Xv, Xt; Root mean square roughness parameter: RMS; Slope parameters: Slpe mx, Slpemx (x), Slperms; Vertex radius error parameter: Radius Err	
		Filter	Gaussian filter, 2RC filter, zero phase filter	
	Sampl	ing Length	0.008, 0.08, 0.25, 0.8, 2.5, 8.0 or 25mm Selectable	
	Evalua	tion Length	Auto calculation	
Size(L×W×H)			600×350×890(mm)	
	Weight		195kg	

- *1 The accuracy is based on the measurement standard gauge block.
- *2 The accuracy is based on the Pt test of standard ball smaller than diameter 25mm.
- *3 The accuracy is based on the verification of the Φ 50mm standard ball with the arc exceeds 90 degrees.
- *4 The accuracy is based on the measurement of the angle of polygonal prism.
- *5 The accuracy is based on the measurement of optical flat.
- *6 The accuracy is based on the measurement of standard roughness block.
- *7 The repeatability is based on the measurement of 0.1-0.2µm square wave roughness block and standard step height block.
- *8 The accuracy is is based on the measurement of 1nm level roughness block and optical flat.

Model No.			SJ5720-OPT200	
		X	0~200mm	
	Measuring	Z	0~500mm	
	Range	Z1	±6mm (Optional: ±12mm)	
	Res	olution	0.001um	
		Z1* ¹	≤± (0.5+0.03 H) μm (H, mm)	
	Accuracy	Pt*2	Pt≤0.2μm	
Contour	Accuracy	Standard Ball*3	≤±(1+R/20) μm (R,mm)	
Measurement		Angle*4	≤±1′	
	Moving	X	0~20mm/s	
	Speed	Z	0~20mm/s	
	Scann	ing Speed	0.05~5mm/s	
	X Stra	aightness*5	≤0.25µm/200mm	
	Measuring Force		0.5mN, 0.75mN, 1mN, 2mN, 3mN(Adjustable)	
	Ra Masurement Range		Ra0.012μm~Ra12.5μm	
	Accuracy*6		Ra0.012μm ~ Ra3 . 2 μm: ≤±(3nm+2.0%A),A(Ra)μm Ra3.201μm ~ Ra12.5μm : ≤±(3nm+3.5%A),A(Ra)μm	
	Repeatability (1δ)* ⁷		1δ≤1nm	
	Measurement Residual*8		Rq≤3nm	
Roughness Measurement	Roughness Parameters		R Roughness: Rp,Rv,Rz,Rc,Rt,Ra,Rq,Rsk,Rku,RSm,RPc,Rdq,Rdc,Rmr,Rmax,Rpm,tp,Htp,Pc,Rda,Ry,Sm,S,Rpc,RzJ; Key Roughness: Rk,Rpk,Rvk,Rpkx,Rvkx,Mr1,Mr2,A1,A2,Vo; Profile: Pa,Pq,Pt,Pz,Pp,Pv,PSm,Psk,Pku,Pdq,Pdc,Pc,PPc,Pmr,Rad,PzJ,Pmax; Waviness of Profile: Wa,Wq,Wt,Wz,Wp,Wv,WSm,Wsk,Wku,Wdq,Wdc,Wmr,Wpc,W	
			Motif: R,AR,W,AW,Rx,Wx,Wte; Standards: GB/T 3505-2009,ISO 4287:1997,ISO13565-2:1996,ASME B46.1-2002, DIN EN ISO 4287:2010,JIS B 0601:2013,JIS B 0601-1994, JIS B 0601-1982,ISO 1302:2002	
	Aspheric Masurement Parameters		Micro profile parameters: Pt, Pa, Fig;Inclination parameters: Smx , Smn ; Horizontal axis angle parameter: Tilt; Distance parameters between the optical axis and the contour: Xp , Xv , Xt Root mean square roughness parameter: RMS; Slope parameters: Slpe mx , Slpemx (x), Slperms; Vertex radius error parameter: Radius Err	
	I	Filter	Gaussian filter, 2RC filter, zero phase filter	
	Sampl	ing Length	0.008, 0.08, 0.25, 0.8, 2.5, 8.0 or 25mm Selectable	
	Evaluat	tion Length	Auto calculation	
	Size(L×W	×H)	800×500×1080(mm)	
	Weigh	t	265kg	

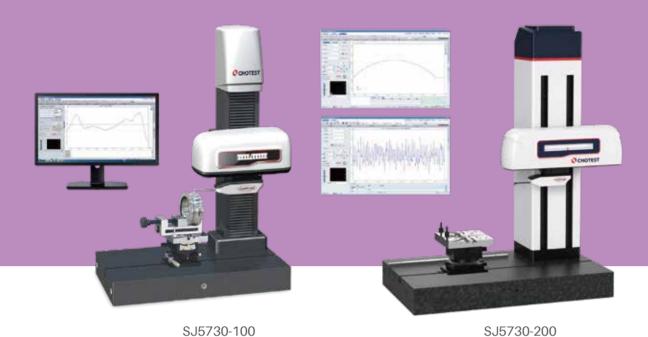
- *1 The accuracy is based on the measurement standard gauge block.
- *2 The accuracy is based on the Pt test of standard ball smaller than diameter 25mm.
- $\star 3$ The accuracy is based on the verification of the Φ 50mm standard ball with the arc exceeds 90 degrees.
- *4 The accuracy is based on the measurement of the angle of polygonal prism.
- *5 The accuracy is based on the measurement of optical flat.
- *6 The accuracy is based on the measurement of standard roughness block.
- *7 The repeatability is based on the measurement of 0.1-0.2µm square wave roughness block and standard step height block.
- $\star 8$ The accuracy is is based on the measurement of 1nm level roughness block and optical flat.





Profilometer SJ5730

Once Scanning for both Profile and Roughness



Functions

Paran	neter classification	Parameters
	Contour Evaluation	P(Original profile), R(Surface roughness profile), W(Waviness)
	Rougness Evaluation	Ra, Rp, Rv, Rz, Rt, Rmax, Rq, Rsk, Rku, RSm, RPc, Rdq, Rdc, Rmr, Motif parameters, RCore parameters, P parameters, W parameters
	Filter	2RC filtering, Gaussian filtering and Zero phase filtering
	Cut-off Wavelength λs	0.008, 0.025, 0.08, 0.25, 0.8, 2.5, 8mm selectable
Roughness Measurement	λs	0.25, 0.8, 2.5, 8, 25um selectable, comply with the specifications of JJF 1099-2018, ISO 4288-1996, GBT 1031-2009
	Shape Error	Aspheric surface shape error measurement, linear shape error measurement, arc surface shape error measurement
	Standard	DIN EN ISO 4287:2010, ASME B46.1-2002, JIS B 0601:2013, GB/T 3505-2009, ISO 4287:1997, ISO 13565-2:1996, ISO 1302:2002
	Common tools	Provides 76 tools, including coordinate creation, construction tools, auxiliary tools, annotations, and geometric tolerances
	CNC Function	Provide CNC measurement mode for batch measurement
Contour Measurement	Custom Meas.	Customize the measurement process according to the characteristics of the workpiece (such as surface with hole in the center), avoids the unnecessary measurement area and perform discontinuous measurement.
	Special Tools	Ball screw measurement (corrected helix angle), thread measurement, stage height, groove depth, groove width, area, convexity etc

Application







Ra of gear tooth surface



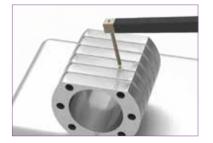
Ra of engine blade



Ra & Profile of mold



Profile & Roughness of car parts



Profile & Roughness of workpiece

Features

- 1. Evaluate Contour and roughness parameters at the same time after once scanning
- 2. High precision, high stability, and high repeatability
- 3. Intelligent management and advanced software analysis system
- 4. Intelligent protection system during scanning
- 5. Flexible manual control
- 6. Nano-scale large roughness measuring range
- 7. Plug-in probe, easy to replace probe
- 8. Extremely small measuring force to avoid scratching the surface

Parameters

Mo	del No.		SJ5730-100	
		X	0~100mm	
	Measuring Range	Z	0~300mm	
	narige	Z1	±6mm (Optional: ±12mm)	
	Res	olution	0.001um	
		Z1* ¹	≤± (0.5+0.03 H) μm (H, mm)	
	Acquirect	Pt*2	Pt≤0.2μm	
Contour	Accuracy	Standard Ball*3	$\leq \pm 1 \mu m (R \leq 10 mm) ; \leq \pm (0.17 + R/12) \mu m (10 < R \leq 200 mm)$	
Measurement		Angle*4	≤±1′	
	Moving	X	0~20mm/s	
	Speed	Z	0~20mm/s	
	Scann	ing Speed	0.05~5mm/s	
	X Stra	aightness*5	≤0.2µm/100mm	
	Measu	iring Force	0.5mN,0.75mN,1mN,2mN,3mN(Adjustable)	
	Ra Masurement Range		Ra0.012μm~Ra12.5μm	
	Accuracy*6		Ra0.012μm ~ Ra3 , 2 μm: \leq ± $(3nm+2.0%A)$, A(Ra)μm Ra3.201μm ~ Ra12.5μm: \leq ± $(3nm+3.5%A)$, A(Ra)μm	
	Repeatability (1δ)* ⁷		1δ≤1nm	
	Measurement Residual*8		Rq≤3nm	
	Roughness Parameters		R Roughness: Rp,Rv,Rz,Rc,Rt,Ra,Rq,Rsk,Rku,RSm,RPc,Rdq,Rdc,Rmr,Rmax,Rpm,tp,Htp,Pc,Rda,Ry,Sm,S,Rpc,RzJ;	
			Key Roughness: Rk,Rpk,Rvk,Rpkx,Rvkx,Mr1,Mr2,A1,A2,Vo;	
Roughness Measurement			Profile: Pa,Pq,Pt,Pz,Pp,Pv,PSm,Psk,Pku,Pdq,Pdc,Pc,PPc,Pmr,Rad,PzJ,Pmax; Waviness of Profile: Wa,Wq,Wt,Wz,Wp,Wv,WSm,Wsk,Wku,Wdq,Wdc,Wmr,Wpc,Wc; Motif: R,AR,W,AW,Rx,Wx,Wte; Standards:	
			GB/T 3505-2009,ISO 4287:1997,ISO13565-2:1996,ASME B46.1-2002, DIN EN ISO 4287:2010,JIS B 0601:2013,JIS B 0601-1994, JIS B 0601-1982,ISO 1302:2002	
	Aspheric Masurement Parameters		Micro profile parameters: Pt, Pa, Fig; Inclination parameters: Smx, Smn; Horizontal axis angle parameter: Tilt; Distance parameters between the optical axis and the contour: Xp, Xv, Xt; Root mean square roughness parameter: RMS; Slope parameters: Slpe mx, Slpemx (x), Slperms; Vertex radius error parameter: Radius Err	
		Filter	Gaussian filter, 2RC filter, zero phase filter	
	Sampl	ing Length	0.008, 0.08, 0.25, 0.8, 2.5, 8.0 or 25mm Selectable	
	Evaluat	tion Length	Auto calculation	
	Size(L×W	×H)	600×350×890(mm)	
	Weigh	t	110kg	

Profilometers

- *1 The accuracy is based on the measurement standard gauge block.
- *2 The accuracy is based on the Pt test of standard ball smaller than diameter 25mm.
- *3 The accuracy is based on the verification of the Φ 50mm standard ball with the arc exceeds 90 degrees.
- *4 The accuracy is based on the measurement of the angle of polygonal prism.
- *5 The accuracy is based on the measurement of optical flat.
- *6 The accuracy is based on the measurement of standard roughness block.
- *7 The repeatability is based on the measurement of 0.1-0.2µm square wave roughness block and standard step height block.
- *8 The accuracy is is based on the measurement of 1nm level roughness block and optical flat.

Model No.			SJ5730-200	
		X	0~200mm	
	Measuring	Z	0~500mm	
	Range	Z1	±6mm (Optional: ±12mm)	
	Res	olution	0.001um	
		Z1* ¹	≤± (0.5+0.03 H) µm (H, mm)	
	A	Pt*2	Pt≤0.2μm	
Contour	Accuracy	Standard Ball*3	≤±1μm(R≤10mm); ≤±(0.17+R/12)μm(10 <r≤200mm)< td=""></r≤200mm)<>	
Measurement		Angle*4	≤±1′	
	Moving	X	0~20mm/s	
	Speed	Z	0~20mm/s	
	Scann	ing Speed	0.05~5mm/s	
	X Stra	aightness* ⁵	≤0.35µm/200mm	
	Measuring Force		0.5mN,0.75mN,1mN,2mN,3mN(Adjustable)	
	Ra Masurement Range		Ra0.012μm~Ra12.5μm	
	Accuracy*6		Ra0.012μm ~ Ra3 . 2 μm: \leq ±(3nm+2.0%A),A(Ra)μm Ra3.201μm ~ Ra12.5μm : \leq ±(3nm+3.5%A),A(Ra)μm	
	Repeatability (1δ)* ⁷		1δ≤1nm	
	Measurement Residual*8		Rq≤3nm	
Roughness Measurement	Roughness Parameters		R Roughness: Rp,Rv,Rz,Rc,Rt,Ra,Rq,Rsk,Rku,RSm,RPc,Rdq,Rdc,Rmr,Rmax,Rpm,tp,Htp,Pc,Rda,Ry,Sm,S,Rpc,RzJ; Key Roughness: Rk,Rpk,Rvk,Rpkx,Rvkx,Mr1,Mr2,A1,A2,Vo; Profile: Pa,Pq,Pt,Pz,Pp,Pv,PSm,Psk,Pku,Pdq,Pdc,Pc,PPc,Pmr,Rad,PzJ,Pmax; Waviness of Profile: Wa,Wq,Wt,Wz,Wp,Wv,WSm,Wsk,Wku,Wdq,Wdc,Wmr,Wpc,WMotif:R,AR,W,AW,Rx,Wx,Wte; Standards: GB/T 3505-2009,ISO 4287:1997,ISO13565-2:1996,ASME B46.1-2002,	
	Aspheric Masurement Parameters		DIN EN ISO 4287:2010, JIS B 0601:2013, JIS B 0601-1994, JIS B 0601-1982, ISO 1302:2002 Micro profile parameters: Pt, Pa, Fig; Inclination parameters: Smx, Smn; Horizontal axis angle parameter: Tilt; Distance parameters between the optical axis and the contour: Xp, Xv, Xt; Root mean square roughness parameter: RMS;	
		Filter	Slope parameters: Slpe mx , Slpemx (x), Slperms; Vertex radius error parameter: Radius Err Gaussian filter, 2RC filter, zero phase filter	
	Sampl	ing Length	0.008, 0.08, 0.25, 0.8, 2.5, 8.0 or 25mm Selectable	
	Evalua	tion Length	Auto calculation	
	Size(L×W	×H)	800×500×1080(mm)	
	Weigh	t	180kg	

- *1 The accuracy is based on the measurement standard gauge block.
- *2 The accuracy is based on the Pt test of standard ball smaller than diameter 25mm.
- $\star 3$ The accuracy is based on the verification of the Φ 50mm standard ball with the arc exceeds 90 degrees.
- *4 The accuracy is based on the measurement of the angle of polygonal prism.
- $\star 5$ The accuracy is based on the measurement of optical flat.
- *6 The accuracy is based on the measurement of standard roughness block.
- *7 The repeatability is based on the measurement of 0.1-0.2µm square wave roughness block and standard step height block.
- $\star 8$ The accuracy is is based on the measurement of 1nm level roughness block and optical flat.





Profilometer SJ5760 Series

Independent Profile and Roughness Measurement Module



Application









Thread workpiece





Ballscrew





Plastic part



Engine cylinder





Custom bearing



Mold



Machining part Roughness specimen



Die casting

Software

Surf & Rough X is an user-friendly and powerful software, which is completely developed by Chotest. It can analyze not only surface contour, but also evaluate surface roughness. Surf & Rough X contains 76 kinds of utility tools, such as coordinate system, construction tools, geometric tolerance, surface roughness assessment tools, etc. CNC measurement mode is a convenient function for batch measurement, and it improves measurement efficiency greatly. Moreover, discontinuous measurement function is also available for the special workpieces.

Functions





















Straightness, roundness, position degree, parallelism, perpendicularity, profile tolerance, etc.

The measurement process can be customized according to the characteristics of the workpiece (Set the probe to jump deep holes, steep slopes or obstacles).

The one-key measurement program can be built for batch measurement. If the tolerance is also entered to the program, the measurement result will be automatically judged as OK or NG.

Coordinate system could be established by point-line or line-line, and it could be translated and rotated.

Ball screw shaft measurement (corrected helix angle), thread measurement, step height, groove depth, groove width, area, curvature, etc.

Export report in .doc, .xls or .pdf, and support user-defined report template.

After import CAD drawing to the software, the user can compare the difference between drawing and scanning contour.

Ra, Rp, Rv, Rz, Rt, Rmax, Rq, Rsk, Rku, RSm, RPc, Rdq, Rdc, Rmr, Pa,Pq, Pt, Pp, Pv, Psm, Psk, Pku, Pdq, Plq, Pdc, PHSC, Ppc, PMr, Waviness of Profile, Motif,







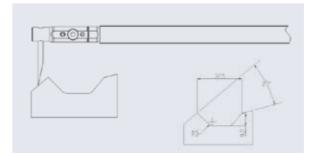


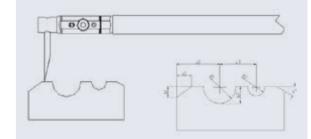






Profile Example

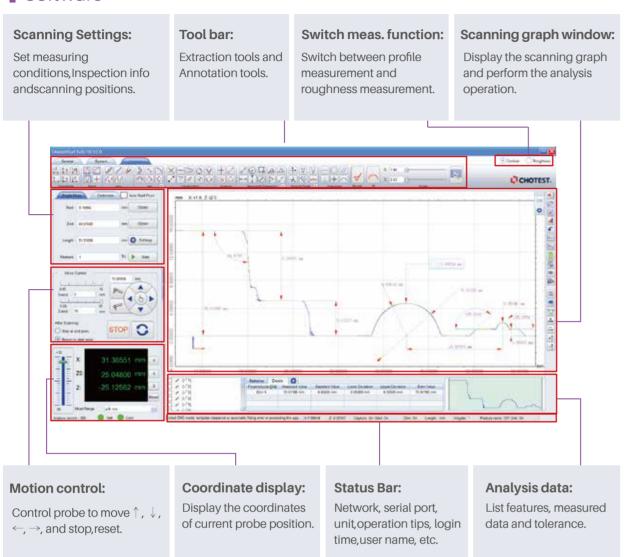




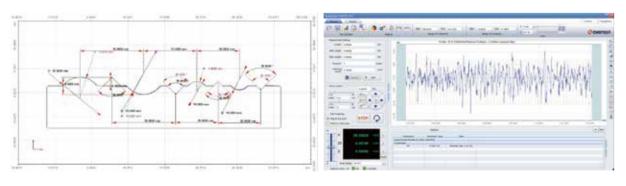




Software



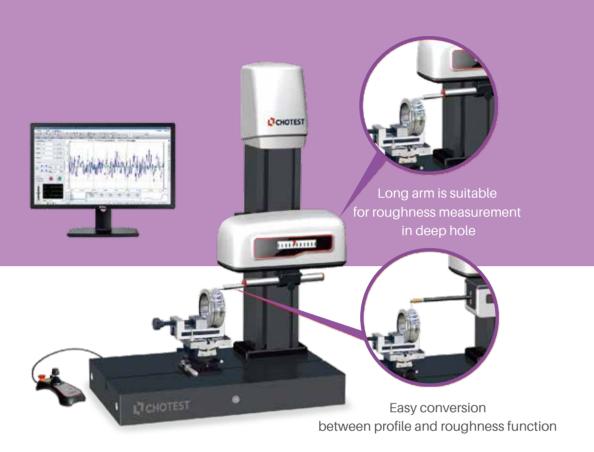
Measurement Interface



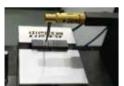
Contour measurement Roughness measurement

I	Model No.	SJ5760-PR		
Travel	Χ	0~200mm		
Range	Z	0~450mm		
	Size(L×W×H)	800×450×1100mm		
	Weight	220Kg		
Contour	Measurement(SJ5760-P)			
Measuring	Z1	±25mm		
Range	Resolution	0.001um		
	X	±(0.6+0.015L)μm(L, mm)		
ll: +:	Z1	±(0.6+0.05H)μm(H, mm)		
Indication Error	Standard Ball	≤±(1+R/15)µm(R,mm)		
	Angle error	≤±1′		
Moving	X	0~20mm/s		
speed	Z	0~20mm/s		
	Scanning Speed	0.05~5mm/s		
	Max Slope	Uphill 77°, downhill 88°		
	Straightness	≤1µm/200mm		
	Scanning Force	10~150mN adjustable		
Roughness	Measurement(SJ5760-R)			
	ZO	±400μm(Optional:±1000μm)		
Measuring Range	Sensor Type	Railless		
ago	Ra Range	Ra0.1μm~Ra64μm		
S	Scanning Force	1mN		
Resolution	ZO	0.001um		
	Indication Error	≤±(5nm+2.5%A)μm, A(Ra)μm		
	Repeatablity	≤1nm		
	Scanning Speed	0.05~0.5mm/s		
Me	asurement Residual	≤0.005µm		
Roughness Parameters		R Roughness: Rp,Rv,Rz,Rc,Rt,Ra,Rq,Rsk,Rku,RSm,RPc,Rdq,Rdc,Rmr,Rmax,Rpm,tp,Htp,Pc,Rda,Ry,Sm,S,Rpc,RzJ; Key roughness: Rcore: Rk,Rpk,Rvk,Rpkx,Rvkx,Mr1,Mr2,A1,A2,Vo; Profile: Pa,Pq,Pt,Pz,Pp,Pv,PSm,Psk,Pku,Pdq,Pdc,Pc,PPc,Pmr,Rad,PzJ,Pmax; Waviness of Profile: Wa,Wq,Wt,Wz,Wp,Wv,WSm,Wsk,Wku,Wdq,Wdc,Wmr,Wpc,WMotif: R,AR,W,AW,Rx,Wx,Wte;		
	Filter	2RC filtering, Gaussian filtering and Zero phase filtering		
	Sampling Length	0.008, 0.08, 0.25, 0.8, 2.5, 8.0 or 25mm Selectable		
Е	Evaluation Length	Auto calculation		
Film Thickness	Measuring Range	60μm or less		
HILKHESS		2%H(H is measuring height in μm)		

SJ5718 Series **Economic Profilometers**



Application

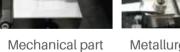




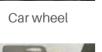


Die casting part





Metallurgy part







Thread part

Battery housing

Phone housing

Machining part

Gearbox pulley

N	Model No.	SJ5718-PR	
Travel	Χ	0~100mm	
Range Z		0~300mm	
S	ize(L×W×H)	600×350×890mm	
	Weight	115Kg	
Contour	Measurement(SJ5718-P)		
Measuring	Z1	±30mm	
Range	Resolution	0.001um	
	X	±(0.6+0.02L)μm(L,mm)	
	Z1	±(0.6+0.05H)µm(H,mm)	
Indication Error	Standard Ball	≤±(1.2+R/15)µm(R,mm)	
	Angle error	≤±1′	
Moving	X	0~20mm/s	
speed	Z	0~20mm/s	
Sca	nning Speed	0.05~5mm/s	
Max Slope		Uphill 77°, downhill 88°	
Straightness		≤0.5μm/100mm	
Scanning Force		30mN	
	Measurement(SJ5718-R)		
	Z0	±400μm(Optional:±1000μm)	
Measuring	Sensor Type	Railless	
Range	Ra Range	Ra0.1μm~Ra64μm	
Sc	canning Force	1mN	
Resolution	Z0	0.001um	
In	dication Error	≤±(5nm+2.5%A)μm, A(Ra)μm	
	Repeatablity	≤1nm	
Sc	anning Speed	0.05~0.5mm/s	
	urement Residual	≤0.005µm	
Roughness Parameters		R Roughness: Rp,Rv,Rz,Rc,Rt,Ra,Rq,Rsk,Rku,RSm,RPc,Rdq,Rdc,Rmr,Rmax,Rpm,tp,Htp,Pc,Rda,Ry,Sm,S,Rpc,RzJ; Key roughness: Rcore: Rk,Rpk,Rvk,Rpkx,Rvkx,Mr1,Mr2,A1,A2,Vo; Profile: Pa,Pq,Pt,Pz,Pp,Pv,PSm,Psk,Pku,Pdq,Pdc,Pc,PPc,Pmr,Rad,PzJ,Pmax; Waviness of Profile: Wa, Wq,Wt,Wz,Wp,Wv,WSm,Wsk,Wku,Wdq,Wdc,Wmr,Wpc,Wc Motif: R,AR,W,AW,Rx,Wx,Wte;	
	Filter	2RC filtering, Gaussian filtering and Zero phase filtering	
Sa	impling Length	0.008, 0.08, 0.25, 0.8, 2.5, 8.0 or 25mm Selectable	
Ev	aluation Length	Auto calculation	
Film Thickness	Measuring Range	60μm or less	
Measurement	Measuring Accuracy	2%H(H is measuring height in μm)	

Stylus Nano Profiler CP200

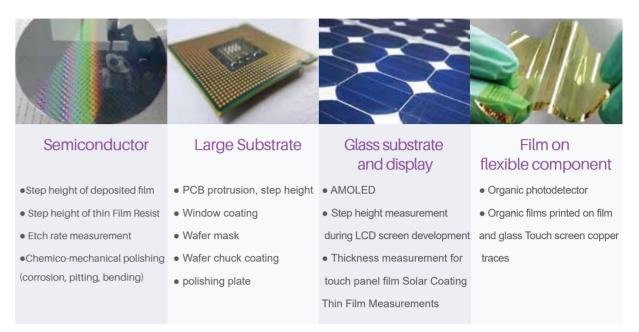
Surface micro-nano profile measurements



Description

Stylus Nano Profiler CP200 is an ultra-precision contact measuring instrument for measurement of surface roughness and microscopic profile, such as micro-nano step height, film thickness. The CP200 uses a displacement sensor with sub-angstrom resolution, ultra-low noise signal acquisition, ultra-fine motion control, and calibration algorithms technology with excellent performance. Its contact force is extremely small, and there are no special requirements for measuring surface reflection characteristics, material types, and material hardness, consequently, it is widely used to measure microscopic surface for industries of semiconductors and compound semiconductors, high-brightness LEDs, solar energy, MEMS micro-electromechanical systems, touch screens, automotive and medical equipment.

Application



Model No.		CP200		
Measurement technology		Stylus Scanning		
Navi	gation Camera	5MP pixels colorful camera, FOV 2200×1700μm		
	Sensor	Ultra Low Inertia, LVDC Sensor		
Mea	asuring Force	1-50mg Adjustable		
	Stylus	Tip radius 2μm , angle 60°		
Object	XY Travel Range	150mm×150mm, Motorized		
Table	Rotation	0~360°, Motorized		
Max S	canning Length	55mm		
Max Sample Height		50mm		
Ma	ax Wafer Size	150mm(6"), 200mm(8")		
Step He	ight Repeatability	5 Å @ Range 330μm/ 10 Å @ Range 1mm (Measure step height 1μm, 1δ)		
Ser	nsor Range*1	330μm or 1mm		
Verti	cal Resolution	Resolution<0.01 Å(When the grade is 13µm)		
Sca	nning Speed	2μm/s~10mm/s		
Si	ze(L×W×H)	640×626×534mm		
	Weight	40kg		
	Input	AC100~240 V, 50/60 Hz, 200W		
Working environment		Humidity: 30~40% RH(No condensation), Temp.: 16~25°C(Fluctuation < 2°C/h), Audio noise: ≤80dl Ground vibration: 6.35μm /s(1~ 100Hz), Air laminar flow: ≤ 0.508 m/s(Downward flow)		

^{*1} The sensor range can only be selected either 330µm or 1mm.

Machine Tool Probes PO Series

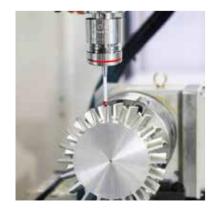
Precision, Reliable

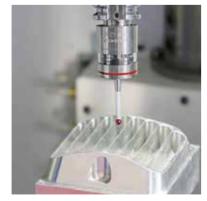


PO series contains 3-point trigger unit inside the probe, which is the most stable structure. When the stylus is moved radially or axially by triggered. Then the circuit inside of probe sends a triggering signal to quently the present coordinates of according to the coordinate records

Features

- High repeatability: One-way repeatability <1µm
- Long standby time: As long as 6 months
- Omnidirectional energy-absorbing design: 360° omnidirectional energy-absorbing design, which helps to cushion the spindle in impact when an operating accident occurs
- Waterproof design: IP68 for probe and receiver
- Intelligent LED indicators: Show current working status of the probe







Parameters

1) Storage temperature: (-25~70)°C

2) Working temperature: (5~55)°C

Model No.	PO40	PO60	PO40L
Size	Ф40mm×L50mm	Ф63mm×L76mm	Ф40mm×L52mm
Weight(Without Holder)	260g	880g	280g
Transmission Type	360° IR	360° IR	360° IR
Transmission Distance	5m	6m	5m
Starting Mode	Code M	Code M, Revolve	Code M
Rotational Speed	Max 1000rev/min	Max 1000rev/min	Max 1000rev/min
Power Supply	1/2AA 3.6V battery×2	AA1.5V/3.6V battery×2	1/2AA 3.6V battery×2
Triggering Direction	±X/±Y/-Z	±X/±Y/-Z	±X/±Y/-Z
Repeatability of $*1$ One-way triggering 2 δ	1µm	2µm	1µm
Max overrun*2	XY:12.5mm +Z:6mm	XY:21mm +Z:11mm	XY:12mm +Z:6mm
XY Trigger Force*3	0.5N~ 0.9N	0.5N~1.6N Adjustable	0.3N~1.6N Adjustable
Z Trigger Force	5.8N	3.5N~14N Adjustable	4N~10N Adjustable
Application	Small and mediumsized 3-axis, 5-axis machining center	Large gantry machine tool, horizontal machining center	CNC lathe or turning-milling composite machining center

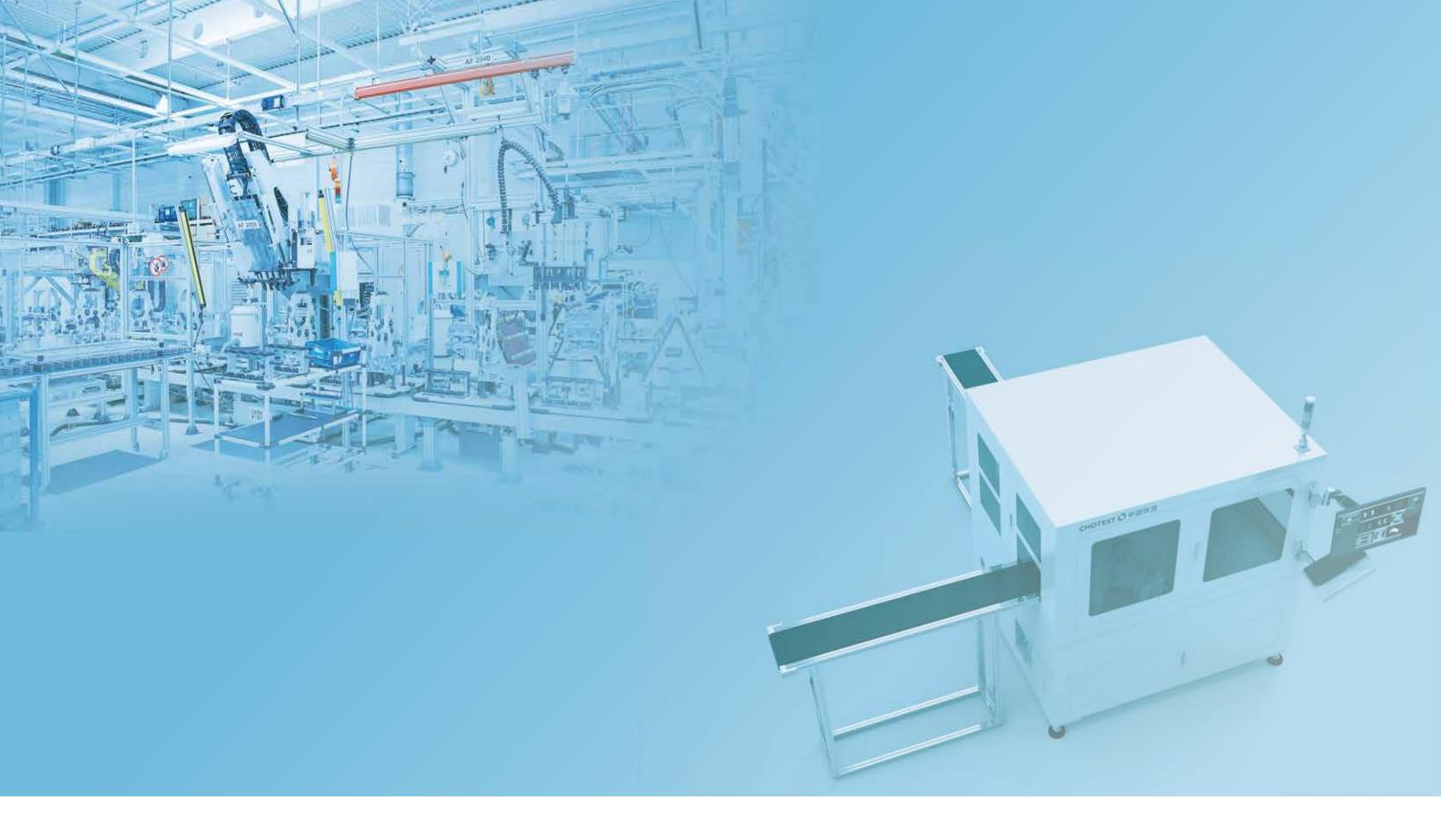
- *1: Test with a 50mm straight stylus under speed 480mm/min
- *2: Test with a 50mm straight stylus
- *3: Test with a 50mm straight stylus under speed 480mm/min

Parameters of Receiver

- 1) Transmission type: IR, 360°
- 2) Working range: Max 8m
- 3) Weight: 926g
- 4) Input voltage: 12V~ 30V
- 5) Input current: <100mA, receiving <40mA
- 6) Cable to machine controller: dedicated 13PIN shielded cable, 8 meters or 15 meters
- 7) Storage temperature: (-25~70)°C, working temperature: (5~55)°C

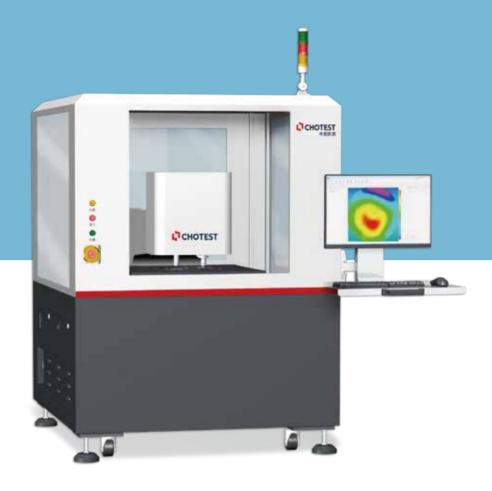


COMI Receiver



Professional Inspection Equipment

WD4000 Series Unpatterned Wafer 3D Inspection System

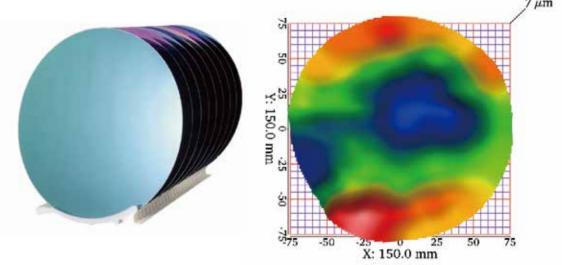


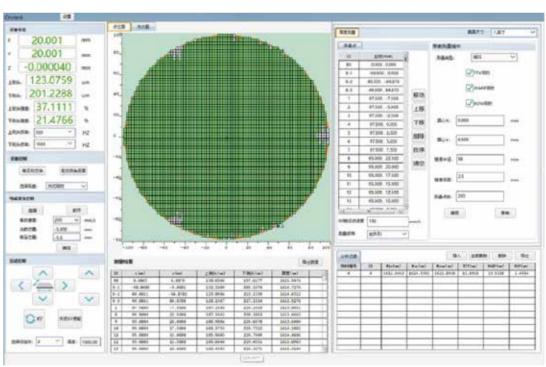
Description

Unpatterned Wafer 3D Inspection System WD4000 series can automatically measure wafer thickness, surface roughness, and micro-nano 3D microtopography at a time. Use white light confocal probes to measure wafer thickness, TTV, LTV, BOW, WARP, line roughness; use white light interferometry probe to scan the Wafer surface to create a 3D profile image of the surface, then analyze the roughness and relevant 2D and 3D parameters according to ISO/ASME/EUR/GBT standards.

Application

Thickness and warpage measurement for unpatterned wafer





Measurement results of wafer thickness and warpage

The 3D shape based on the upper and lower surfaces of the wafer is reconstructed by non-contact measurement. The powerful measurement and analysis software ensures the stable calculation for the thickness, roughness, total thickness variation(TTV) of the wafer.

Inspection

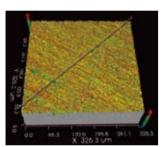
Equipment

Application

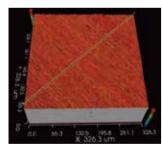
Roughness measurement for unpatterned wafer



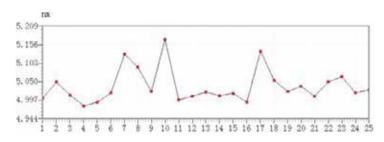
Thinned silicon wafer



3D image of rough grinding silicon wafer



3D image of fine grinding silicon wafer



Sa curve of 25 times measurement data for fine grinding wafer

	文件				30仲数分析		
10	88	Bhi	Sqi高度更良(I	Sp(高度を設)[L	SVERBBRIS.	Sz[馬鹿伊敦](IS	SA(毛度を取扱
1	10.1		7.597	25.179	319.103	344.283	5.004
2.	10,2	-	8.288	24,684	319.429	344.113	5.050
\$1.	50,3		7.092	24,394	316.219	340.633	5.012
4	50,4	-	6.772	25.329	320.325	345,654	4.982
50	10,5		6.999	24.388	318.774	343.162	4.992
6	10,6		7.330	24.164	316.117	345.280	5.019
7.	10,7		9.190	24,424	308.329	332.754	5,129
8	10,3		8.700	24,930	319.030	343.961	5,092
9	54,3		7.583	25.466	313.352	338.818	5.022
10	sa_10		9.636	24.834	318.285	347.119	5.171
11	14,11	- 5	7,269	25.343	318.515	343.858	4,998
12	50,12		7.149	25.556	318.074	343.630	5.009
13	14,13		7.425	24,911	318.300	343.211	5.021
14	59_14		7.461	25.519	218.559	344.078	5.011
13	sa_15	-	7.340	24.668	318-259	342.927	5.017
16.	10,18		6.986	24,730	312.806	337.536	4.992
17	ta_17	- 5	9.301	24.702	111-648	338.350	5.137
18	14_18		7,826	25,371	134.494	339.766	5.054
19	sa_19	-	7.294	24.903	313.570	338.472	5.022
25	ta_20	-	7.684	24,940	116.621	341.563	5.038
21	10,21	-	7.260	25.037	\$10.442	115.479	5.009
22	sa,22	-	7,757	25.130	815.120	340,250	5.049
23	14,23	- 59	8,493	24,773	316.354	341.127	5.064
24	50,24		7.373	24,986	316.743	341,729	5.018
25	14,25		7.545	25.111	\$16.827	341.933	5,028
	15.IT	平均	7,734	24.935	316.292	341.227	5.038

Multi-file analysis of 25 times measurement data for fine grinding wafer

During rough grinding and fine grinding process for the Wafer thinning, the surface roughness Sa values and their stability are used to evaluate the processing quality. When the thinned silicon wafer is measured in the strong noise environment of the production workshop, the roughness Sa values of the fine grinding silicon wafers are ranging around 5nm, and the repeatability is 0.046987nm based on 25times of measurement data which proves the measurement stability is good.

M	lodel No.	WD4100	WD4200	
	/afer Size	4", 6", 8", 12"		
	afer Table	Vacuum chuck		
Loading	and Unloading	Manual(Auto robot arm is optional)		
	Travel range	400mm/400	·	
	loving speed	500n		
	ain Frame	Mar		
	i-Vibration	Air-floating anti-v		
7	ing capacity			
	verall Size	1500×1500		
	Weight	About 1		
		0.6MPa;		
	pressed Air	Temp. 20°C±1°C/		
	g Environment			
	ent Vibration	VC-C o	Detter	
	rial of Object	Arsenide, nitride, phosp	horus, germanium, phosphorurate,	
	Sensor		e, silicon, silicon carbide, glass, etc.	
			e light confocal sensors n~2000µm	
	suring range nning Path	Full map area scanning, Union Jack path, free multi-point		
		±0.25µm		
	ccuracy atability(σ)	0.2μm		
	esolution		<u> </u>	
	ment Parameters		5nm ion), LTV, BOW, warp, flatness, line roughness	
			ion, ETV, BOW, warp, italiess, the loughness	
	pography Measurement S	System	M/hita light interferements.	
	ement Principle		White light interferometry	
	ht Source		White LED	
	ective Lens		10X(2.5X, 5X, 20X, 50X are optional)	
	ld of View		0.96 mm×0.96 mm	
	ens Turret		Single hole	
	Adjustment		±2°	
	canning Range		5mm	
	s Resolution		0.1nm	
	al Resolution		0.5~3.7μm	
	ning Speed		2.5~5.0μm/s	
	rs of Test Object	_	Reflectivity 0.05%~100%	
Roughness F	RMS Repeatability*1		0.08nm	
Step Height	Accuracy	_	1%	
Measurement*2	Repeatability	—	0.2%1σ	
Measuren	nent Parameters		Microtopography, line/surface roughness, spatial frequency, etc.	

^{*1} Roughness performance is obtained by measuring SQ parameters for a 0.2nm SA silicon wafer in the laboratory environment according to ISO 25178.



^{*2} Step height performance is obtained by measuring a standard 4.7 µm stage block in the laboratory environment according to ISO 5436-1: 2000.

Patterned Wafer Critical Dimension & Overlay Measurement System BOKI_1000



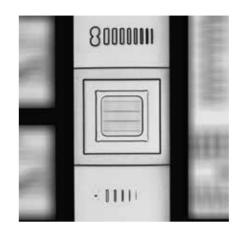
Description

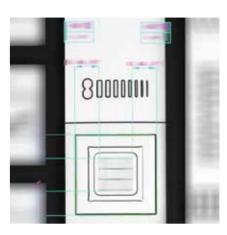
Patterned Wafer Critical Dimension & Overlay Measurement System is an optical inspection instrument that can perform both high-precision XY plane dimension inspection and sub-nanometer surface 3D topography measurement. It can scan multiple regions on a large surface accurately and automatically with excellent repeatability, which significantly increases the measurement efficiency and reduces human error.

Equipping high-resolution optical lens, combining high-precision image analysis algorithm, in CNC mode the system can automatically position & recognize the measuring objects, then automatically measure and evaluate all sizes according to program. At the same time, it integrates white light interferometry measurement system, which can scan the wafer surface to create a 3D profile image of the surface, then analyze Z-direction sizes in nanometer level.

It is widely used in ultra-precision machining industries such as semiconductor manufacturing and packaging process inspection, optical processing, MEMS components, etc.

Application

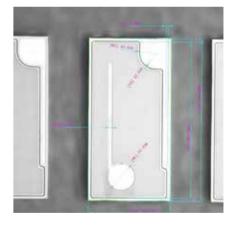




Overlay Offset Measurement

During wafer manufacturing, the offset of the overlay after photoetching process is measured in Photo area, exposure of wafer, and compensation values based on the measurement are imported into the lithography machine to optimize the stability of the wafer photoetching process.





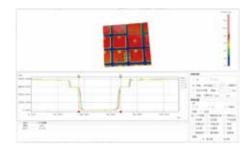
Key Dimensions Measurement

During wafer manufacturing, it requires to control critical dimensions of Die in multiple processes, and SuperView automatically extracts the feature edges of Die, and at the same time it measures all features according to program efficiently and accurately.



Professional

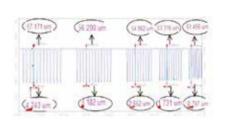
Inspection Equipment



3D Dimensions Measurement

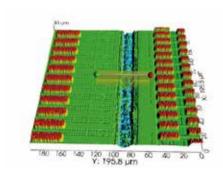
During wafer manufacturing, it is necessary to measure the bottom width of the grooves to check whether the distance between dies is qualified after the previous process in Photo area. The software automatically select multiple parabolas to obtain average value for target positions after auto scanning, then the parameters of the exposure machine is adjusted based on the measurement result in order to meet the process requirements.

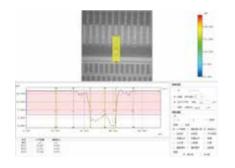




Etch Depth Measurement and Profile Analysis

Reconstruct the 3D image of the wafer, and extract the cross-sectional profile of the groove lines for analysis, then evaluate the integrity of the grooves profile and observe the defect at the bottom of grooves.





Laser Groove Depth and Width Measurement

After the laser engraving process, laser U-groove depth and width should be measured. The software can customize the width of the lasso to extract mean value profile curve of the groove, then calculate the average depth & width values of the groove. The parameters of the laser machine is adjusted to meet the process requirements based on measurement results.

Parameters

	Model No.	BOKI_	1000	
Loading Bin		4 pcs of Cassette, size is customizable		
Feeding Sensor		With anti-skid function		
	Light Source	White/Green LED (singl	e or double is optional)	
Ba	arcode Scanner	Barcode re	ecognition	
\	/ideo System	1024	(1024	
Micr	o Objective Lens	10×, 20)×, 50×	
Meas	surement Accuracy	10X:±0.5μm; 20X:±	0.4μm; 50X:±0.3μm	
Re	peatability(o)*1	10X:±0.2μm; 20X:±	0.2μm; 50X:±0.1μm	
Interfero	metric Objective Lens	2.5×, 5×, 10×, 2	20×, 50×, 100×	
Z	axis Resolution	0.1	nm	
Lateral F	Resolution (0.5λ/NA)	100X~2.5X: (0.5μm~3.7μm	
Roughnes	ss RMS Repeatability*2	0.02	nm	
Surface	Profile Repeatability	0.1	nm	
01	-:	Repeatability	Accuracy	
Step Height Measurement*3		0.2% 1σ	0.8%	
S	oftware	Super	SuperView	
Field of View		0.49×0.49mm (@Optical Zoom 0.75×)		
N	Max Field of View	6×6mm		
L	ens Turret	Manual 3 holes turret(Optional: Motorized 5 holes turret)		
	XY Travel Range	300×3	00mm	
Object	Load Capacity	5kg		
Table	Flatness	<10µm		
	Control Mode	Motorized		
Z-Axis	Travel Range	30mm		
Z-AXIS	Control Mode	Motorized		
Vac	uum Chuck(Optional)	Negative pressure ≤-80KPa		
Over	rall Dimension(L×W×H)	1800×1400×1710mm		
Dı	ustproof Device FFU	Class 1000		
Required [Dust-Free Environment Level	Class 1000		
	Oil-Proof Device	All guide rails must be provided with oil shields, and oil stains an other substances cannot fall out.		
Equipment Weight		800KG		
	Power Supply		HZ,13~14A,3000W	
Compressed Air		1.Air-floating anti-vibration system: Max flow 1.5LPM; Average flow 1LPI Pressure 0.6MPa; Hose diameter 6mm; 2.Vacuum chuck: Max flow 250LPM; Average flow 180LPM; Pressure ≤ -80kpa; Hose diameter 8mm;		
W	orking Environment	Temp.: 15~30°C, humidity:	30~80% (no condensation)	
	Safety	The equipment has door mag		

^{*1} Accuracy and repeatablity are obtained by measuring Standard Resolution Test Board.

^{*2} Roughness Performance is obtained by measuring SQ parameters of a Sa 0.2nm silicon wafer in the laboratory environment according to ISO 25178.

^{*3} Step height performance is obtained by measuring a standard 4.7 µ m stage block in the laboratory environment according to ISO 5436-1: 2000.



Dimensional Calibrators

SJ5100 Series **Universal Length Measuring Machine**

Absolute measurement over entire measuring range



Functions

- 1. Measure gauge blocks, thread gauges, plain gauges, Taper thread/plain gauges, pin gauge, caliper, spline gauges, setting bars, snap gauges, internal/external micrometers, feeler gauges, Dial indicators, dial bore gauge, dial test gauges, internal micrometer three points, etc.
- 2. Measure various gauges according to GB, ISO, BS, ANSI, DIN, JIS, API standards. With comprehensive and professional standards in database, it meets requirements of most customers.
- 3. Conform to a variety of verification regulations & measuring standards. All test results are generated according to relevant regulations and standards.
- 4. User-friendly software.
- 5. With centralized database management for measuring records, the operator can query and manage the measuring records according to object type, testing institution, manufacturing number, inspector, submitted institution, equipment number, inspection date and effective date.
- 6. Support to print multiple selected test records or test certificates from database at once time.
- 7. Support to export test data to Word, Excel, AutoCAD (optional) files.
- 8. Data backup and restore.
- 9. Support user-defined template of report.
- 10. Support user-defined standard/tolerance.

Application









Big plain ring gauge

Spline plug gauge

Spline ring gauge

Taper thread ring gauge







Thread ring gauge

Snap gauge

Caliper

Micrometer 3 points









External micrometer

Setting bar

Small plain ring gauge

Internal micrometer









Long gauge block

Pin gauge

Inner ring of bearing

Taper thread plug gauge









Dial test gauge

Depth micrometer

Digital radius gauge

Carbon fiber comparison gauge

Main Accessories







Workholder for gauge block Workholder for micrometer One-coordinate floating table







V-shaped block



Five-axis object table Workholder for micrometer 3 points



Measuring jaw



Inside measuring device



Ruby probes



Plain/Blade anvil



Spherical anvil & Measuring bar

Software









Model No.		SJ5100-UP300	SJ5100-UP600	SJ5100-UP1000		
Absolute	External range	0-340mm	0-640mm	0-1040mm		
measurement	Internal range	0.7~200mm	0.7~500mm	0.7~900mm		
Indica	ation error	(±(0.09+L/1500)µm (Note: L is measured length in mm)		
Repeat	tability (2s)		0.06µm			
Resol	ution(µm)		0.01µm			
Max pitch diameter(mm)		200mm(Ring)/250mm(Plug)				
Measu	uring force	0.05N, 0.1N, 0.3N, 0.5N, (1~10)N continuously adjustable by hand				
Operation	n environment	20±0.5 °Cfluctuation≤0.2°C /hour, Related Humidity: 20~60%				
Dimer	nsion(mm)	1400×400×450	1400×400×450	1700×400×450		
We	ight(kg)	150kg	150kg	180kg		
	Z-axis range	0~50mm				
	Y-axis range	±25mm				
Fire aria	X-axis floation	±10mm				
Five-axis	Z-axis rotation	±3°				
object table	Y-axis yaw		±3°			
	Loading capacity		≤50kg			
	Dimension		350mm×125mm			

Mod	del No.	SJ5100-300A/B	SJ5100-600A/B	SJ5100-1000A/B	SJ5100-1500A/B	SJ5100-2000A/B	SJ5100-3000A/B
Absolute	External range	0~340mm	0~640mm	0~1040mm	0~1540mm	0~2040mm	0~3040mm
measurement	Internal range	0.7~200mm	0.7~500mm	0.7~900mm	0.7~14000mm	0.7~1900mm	0.7~2900mm
Indication error		A series: $\pm (0.12 + L/1000) \mu m$; B series: $\pm (0.20 + L/1000) \mu m$ (Note: L is measured length in mm)			A series: ±(0.25+L/1000)μm; B series: ±(0.4+L/1000)μm (Note: L is measured length in mm)		
Repeatability (2s)		A Series:0.08µm; B Series 0.10µm A Series:0.15µm; B Series 0.20µm					0.20µm
Resolution(µm)		0.01µm					
Max pitch diameter(mm)		200 mm(Ring)/250mm(Plug)					
Measuring force		0.05N, 0.1N, 0.3N, 0.5N, (1~10)N continuously adjustable by hand					
Operation environment		A series: 20±1°C, fluctuation≤0.2°C /hour, Related Humidity: 20~60% B series: 20±2°C, fluctuation≤0.5°C /hour, Related Humidity: 20~60%					
Dimension(mm)		1400×400×450	1400×400×450	1700×400×450	2200×400×450	2700×400×450	3700×400×450
Weight(kg)		150kg	150kg	180kg	310kg	360kg	410kg
	Z-axis range	0~50mm					
	Y-axis range	±25mm					
Five-axis object table	X-axis floation	±10mm					
	Z-axis rotation	±3°					
	Y-axis yaw	±3°					
	Loading capacity	≤50kg					
	Dimension	350mm×125mm					

SJ5200/SJ5500 Series Universal Thread Measuring Machines



SJ5200



Functions

- 1. Full-automatic measurement for comprehensive parameters of cylindrical thread plug gauges, cylindricalthread ring gauges, taper thread plug gauges, taper thread ring gauges, plain ring gauges, plain pluggauges and other gauges with internal & external dimensions, including virtual pitch diameter, single pitchdiameter, basic pitch diameter, major diameter, minor diameter, thread pitch, thread angle, half of threadangle, flank straightness, lead angle, taper, etc.
- 2. Can measure trapezoidal thread gauges, buttress thread gauges, sawtooth thread gauges and otherlarge-slope thread gauges.
- 3. Can measure comprehensive parameters of single thread and multiple thread.
- 4. Can measure various thread gauges according to GB, ISO, BS, ANSI, DIN, JIS, API standards. Withcomprehensive and professional thread standards in database, it meets requirements of most customers.
- 5. Automatically generate test report according to selected standard.
- 6. After once measurement, the software can calculate various parameters of thread and display data of anyposition, it also could generate the thread curve, relevant parameters and analysis chart automatically.
- 7. Measuring probe and workholder are identified automatically, which avoids collision of measuring probecaused by misoperation.
- 8. One-sided or two-sided measurement and analysis for gauges.
- 9. Controller for measuring pin positioning: with an easy-to-use buttons control box, the operation is moreflexible.
- 10. User-friendly software, simple and easy-to-use.
- 11. Test results are saved automatically with name of measuring series number + size of measuring gauge+ type of measuring gauge. With centralized database management for measuring records, the user canquery and manage the measuring records according to object type, testing institution, manufacturingnumber, inspector, submitted institution, equipment number, inspection date, effective date,
- 12. Can print multiple selected test records or test certificates from database at once time.
- 13. Can export test data to Word, Excel, AutoCAD (optional) files.
- 14. Data backup and restore.
- 15. Can output reports in a variety of formats in Word or PDF, moreover the report format can becustomized.
- 16. Support user-defined standards.

■ SJ5200 Application



Thread plug gauge



Taper plain ring gauge



Plain ring gauge



Taper plain plug gauge

SJ5200 Parameters

Model No.	SJ5200-60	SJ5200-100	SJ5200-160	
External measuring range	(1.0-50)mm	(1.0-90)mm	(1.0-150)mm	
Internal measuring range	(2.5-60)mm	(2.5-100)mm	(2.5-160)mm	
Max scanning range	60mm(Optional 75mm)	60mm(Optional 75mm)	60mm(Optional 75mm)	
Min pitch	0.1mm	0.1mm	0.1mm	
Weight	200kg	250kg	300kg	
Size	1000×450×1000mm	1000×450×1000mm	1000×450×1130mm	
Measurement uncertainty				
Cylindrical or Taper thread ring gauge(Minor diameter>2.5mm,half of thread angle≥27°)				
NA:	0 = 1 /000	0 = 1/000	0 = 1/000	

Cylindrical or Taper thread ring g	gauge(Minor diameter>2.5mm,h	nalf of thread angle≥27°)		
Minor diameter(µm)	2.5 + L/200	2.5 + L/200	2.5 + L/200	
Actual pitch diameter(µm)	2.5 + L/200	2.5 + L/200	2.5 + L/200	
Pitch(µm)	0.75 + L/200	0.75 + L/200	0.75 + L/200	
Cylindrical or Taper thread plug	gauge(Major diameter>1mm,ha	alf of thread		
Major diameter(µm)	2.0 + L/200	2.5 + L/200	2.5 + L/200	
Actual pitch diameter(µm)	2.0 + L/200	2.5 + L/200	2.5 + L/200	
Pitch(µm)	0.75 + L/200	0.75 + L/200	0.75 + L/200	
Cylindrical or Taper plain gauge	(Diameter from 1mm to 10mm)			
Diameter(µm)	1.5 + L/200	2.0+ L/200	2.0+ L/200	
Cylindrical or Taper plain gauge(Diameter>10mm)				
Diameter(µm)	Diameter(µm) 1.0+ L/200		1.5+ L/200	

■ SJ5500 Application



Thread plug gauge





API gauge



API gauge

SJ5500 Parameters

Model No.	SJ5500-200	SJ5500-300	SJ5500-400	SJ5500-500	SJ5500-600
External measuring range	(1.0-250)mm	(1.0-350)mm	(1.0-450)mm	(1.0-550)mm	(1.0-620)mm
Internal measuring range	(2.5-250)mm	(2.5-350)mm	(2.5-450)mm	(2.5-550)mm	(2.5-620)mm
Max scanning range	250mm				
Min pitch	0.1mm				
Weight	2000kg				
Size	2000×900×910mm				
Measurement uncertainty					
Cylindrical or Tapar thread ring gauge (Miner diameters 2 Emm half of thread angles 27°)					

Wedsdreinert uncertainty			
Cylindrical or Taper thread ring gauge(Minor diameter>2.5mm,half of thread angle≥27°)			
Minor diameter(μ m)	3.0 + L/200		
Actual pitch diameter(µm)	3.0 + L/200		
Pitch(µm)	0.8 + L/200		
Cylindrical or Taper thread plug gauge (Major diameter> 1mm, half of thread			
Major diameter(µm)	2.9 + L/200		
Actual pitch diameter(µm)	2.9 + L/200		
Pitch(µm)	0.8 + L/200		
Cylindrical or Taper plain gauge(Diameter from 1mm to 10mm)			
Diameter(µm)	2.0 + L/200		
Cylindrical or Taper plain gauge(Diameter>10mm)			
Diameter(µm)	2.0 + L/200		
·			

SJ2018/2620 **Automated Dial Indicator Testing Machines** Precision, Versatile, Efficient SJ2018

Parameters

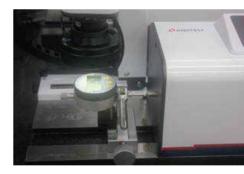
Model No.	SJ2018	SJ2620	
Measuring range	(0-50)mm		
Resolution	0.01µm		
Repeatability	0.1µm		
Reading accuracy	1/60 of division value for Resolution 0.01mm dial indicator 1/30 of division value for Resolution 0.001mm dial indicator		
Indication error	Random 1mm≤0.6µm Random 2mm≤0.6µm Random 10mm≤0.8µm Random 30mm≤0.9µm 50mm≤1µm		
Hysteresis	≤0.5µm		
Interface	RS232 (Can convert to USB)		
Input voltage	AC100~240V,50~60Hz		
Operating environment	Temp.(20±2) °C , RH(50~70)%		
Dimension	640×240×530mm	300×235×640mm	
Weight	35kg	25kg	

SJ2620

Functions

- 1. Measure dial indicators, micrometer dial indicators, dial test indicators, dial bore indicators, automatically according to the elevant regulations and standards.
- 2. Measure the above gauges with digital display automatically.
- 3. Measure the above gauges with imperial system automatically.
- 4. Support semi-auto testing mode.
- 5. Automatic zeroing after click "Start".
- 6. Overtolerance hinting during measuring process.
- 7. Process and qualify the measured data automatically.
- 8. Can search and manage the test records according to object type, manufacturer, serial No.,inspector, applicant, equipment No., inspection date or effective date etc.
- 9. Can print or export former test records including error sheet or curve.
- 10. Can print or export multiple selected test records from database once time.
- 11. Can export test data in CSV, EXCEL, WORD.
- 12. Data backup and restore.
- 13.Can customize format of test report according to requirements of customer.
- 14. Support user-defined testing program and tolerance.

Application



Digital dial indicator



Dial bore indicator

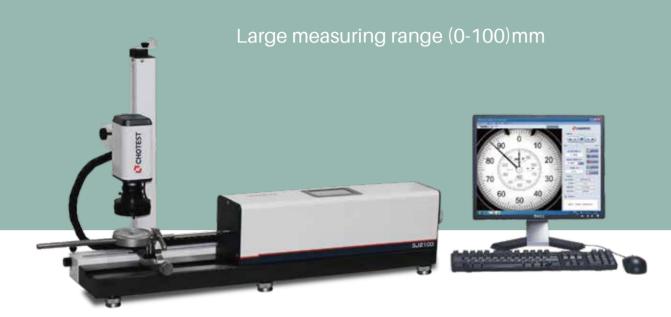


Dial test indicator



Mechanical comparator

SJ2100 Automated Dial Indicator Testing Machines



Parameters

Model No.	SJ2100
Measuring Range	(0-100)mm
Resolution	0.1µm
Repeatability	0.1µm
Reading Accuracy	1/60 of division value for Resolution 0.01mm dial indicator 1/30 of division value for Resolution 0.001mm dial indicator
Indication Error	Random 1mm≤1µm, Random 2mm≤1µm, Random 10mm≤1.5µm Random 30mm≤2µm, Random 50mm≤2.5µm, 100mm≤4µm
Hysteresis	≤ 0.5µm
Interface	RS232 (Can convert to USB)
Input Voltage	AC100~240V, 50~60Hz
Operating Environment	Temp.(20±2)℃, RH(50~70)%
Dimension	700×250×165mm
Weight	30Kg

Workholder for plunger dial indicator

Item No.: SJ20D, SJ20A

Function: For testing of regular dial indicators

Stem diameter of indicator: ⊕8mm



Workholder for lever-type indicator and bore dial indicator

Item No.: SJ20B

Function: For testing of dial test indicators and dial bore indicators

Stem diameter of indicator: $\Phi 4$, $\Phi 6$, $\Phi 8$ mm(dial test indicators); $\Phi 6 \sim \Phi 28$ mm(dial bore indicators)



Extension bar for camera

Item No.: SJ22

Function: For testing of dial bore indicators with long stem







Three balls object table







